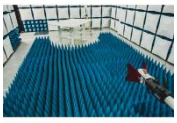
Element Materials Technology
(formerly PCTEST)
18855 Adams Court, Morgan Hill, CA 95037 USA
Tel. 408.538.5600
http://www.element.com



MEASUREMENT REPORT
PART 90

Applicant Name:
Apple Inc.
One Apple Park Way
Cupertino, CA 95014
United States

Date of Testing:
4/18/2024 - 6/24/2024
Test Report Issue Date:
9/6/2024
Test Site/Location:
Element Materials Technology Morgan Hill, CA, USA
Test Report Serial No.:
1C2405200018-12-R2.BCG

FCC ID:	**BCGA2995**
Applicant Name:	**Apple Inc.**

Application Type:	Certification
Model:	A2995, A2996
EUT Type:	Tablet Device
FCC Classification:	PCS Licensed Transmitter (PCB)
FCC Rule Part:	§2.1049, §90(S), §90(R)
Test Procedure(s):	ANSI C63.26-2015, KDB 971168 D01 v03r01

This equipment has been shown to be capable of compliance with the applicable technical standards as indicated in the measurement report and was tested in accordance with the measurement procedures specified in §2.947. Test results reported herein relate only to the item(s) tested.

This revised Test Report (S/N: 1C2405200018-12-R2.BCG) supersedes and replaces the previously issued test report on the same subject device for the same type of testing as indicated. Please discard or destroy the previously issued test report(s) and dispose accordingly.

I attest to the accuracy of data. All measurements reported herein were performed by me or were made under my supervision and are correct to the best of my knowledge and belief. I assume full responsibility for the completeness of these measurements and vouch for the qualifications of all persons taking them.

RJ Ortanez
Executive Vice President

Prepared by: WKR0000007837

Reviewed by: WKR0000005849

ACCREDITED
CERT #2041.02

Unless otherwise specified, no part of this report may be reproduced or utilized in any part, form or by any means, electronic or mechanical, including photocopying and microfilm, without permission in writing from Element Materials Technology. If you have any questions about this or have an enquiry about obtaining additional rights to this report or assembly of contents thereof, please contact ct.info@element.com.

TABLE OF CONTENTS

1.0 INTRODUCTION 4
- 1.1 Scope 4
- 1.2 Element Materials Technology Test Location 4
- 1.3 Test Facility / Accreditations 4

2.0 PRODUCT INFORMATION 5
- 2.1 Equipment Description 5
- 2.2 Device Capabilities 5
- 2.3 Antenna Description 6
- 2.4 Test Support Equipment 6
- 2.5 Test Configuration 7
- 2.6 Software and Firmware 7
- 2.7 EMI Suppression Device(s)/Modifications 7

3.0 DESCRIPTION OF TESTS 8
- 3.1 Evaluation Procedure 8
- 3.2 Radiated Spurious Emissions 8

4.0 MEASUREMENT UNCERTAINTY 9

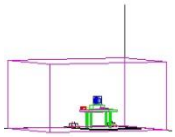
5.0 TEST EQUIPMENT CALIBRATION DATA 10

6.0 SAMPLE CALCULATIONS 11

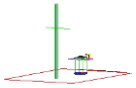
7.0 TEST RESULTS 12
- 7.1 Summary 12
- 7.2 Occupied Bandwidth 14
- 7.3 Spurious and Harmonic Emissions at Antenna Terminal 38
- 7.4 Band Edge Emissions at Antenna Terminal 64
- 7.5 Conducted Power Output Data 80
- 7.6 Radiated Power (ERP) 83
- 7.7 Radiated Spurious Emissions 87
- 7.8 Frequency Stability / Temperature Variation 102

8.0 CONCLUSION 107

Unless otherwise specified, no part of this report may be reproduced or utilized in any part, form or by any means, electronic or mechanical, including photocopying and microfilm, without permission in writing from Element Materials Technology. If you have any questions about this or have an enquiry about obtaining additional rights to this report or assembly of contents thereof, please contact ct.info@element.com.



PART 90 MEASUREMENT REPORT



Mode	Bandwidth	Modulation	Tx Frequency Range [MHz]	Measurement	OBW [MHz]	Max. Power [W]	Max. Power [dBm]	Emission Designator
LTE Band 26	1.4 MHz	QPSK	814.7 - 823.3	Conducted	1.1070	0.337	25.28	1M11G7W
		16QAM	814.7 - 823.3	Conducted	1.1163	0.267	24.27	1M12D7W
		64QAM	814.7 - 823.3	Conducted	1.1115	0.214	23.30	1M11D7W
		256QAM	814.7 - 823.3	Conducted	1.1018	0.112	20.50	1M10D7W
	3 MHz	QPSK	815.5 - 822.5	Conducted	2.7301	0.347	25.40	2M73G7W
		16QAM	815.5 - 822.5	Conducted	2.7259	0.267	24.26	2M73D7W
		64QAM	815.5 - 822.5	Conducted	2.7286	0.218	23.39	2M73D7W
		256QAM	815.5 - 822.5	Conducted	2.7212	0.111	20.44	2M72D7W
	5 MHz	QPSK	816.5 - 821.5	Conducted	4.5531	0.338	25.29	4M55G7W
		16QAM	816.5 - 821.5	Conducted	4.5415	0.269	24.30	4M54D7W
		64QAM	816.5 - 821.5	Conducted	4.5357	0.218	23.39	4M54D7W
		256QAM	816.5 - 821.5	Conducted	4.5361	0.112	20.50	4M54D7W
	10 MHz	QPSK	819.0	Conducted	9.0367	0.330	25.18	9M04G7W
		16QAM	819.0	Conducted	9.0349	0.274	24.38	9M03D7W
		64QAM	819.0	Conducted	9.0431	0.212	23.26	9M04D7W
		256QAM	819.0	Conducted	9.0322	0.110	20.42	9M03D7W
LTE Band 14	5 MHz	QPSK	790.5 - 795.5	ERP	4.5433	0.130	21.15	4M54G7W
		16QAM	790.5 - 795.5	ERP	4.5578	0.103	20.11	4M56D7W
		64QAM	790.5 - 795.5	ERP	4.5495	0.082	19.13	4M55D7W
		256QAM	790.5 - 795.5	ERP	4.5647	0.042	16.28	4M56D7W
	10 MHz	QPSK	793.0	ERP	9.0323	0.127	21.05	9M03G7W
		16QAM	793.0	ERP	9.0302	0.096	19.81	9M03D7W
		64QAM	793.0	ERP	9.0386	0.078	18.93	9M04D7W
		256QAM	793.0	ERP	9.0426	0.041	16.14	9M04D7W
NR Band n14	5 MHz	π/2 BPSK	790.5 - 795.5	ERP	4.4837	0.129	21.12	4M48G7W
		QPSK	790.5 - 795.5	ERP	4.4994	0.130	21.15	4M50G7W
		16QAM	790.5 - 795.5	ERP	4.4984	0.103	20.14	4M50D7W
		64QAM	790.5 - 795.5	ERP	4.4757	0.082	19.15	4M48D7W
		256QAM	790.5 - 795.5	ERP	4.4587	0.082	19.15	4M46D7W
	10 MHz	π/2 BPSK	793.0	ERP	8.9716	0.126	21.02	8M97G7W
		QPSK	793.0	ERP	9.3022	0.124	20.94	9M30G7W
		16QAM	793.0	ERP	9.2840	0.104	20.19	9M28D7W
		64QAM	793.0	ERP	9.2728	0.081	19.09	9M27D7W
		256QAM	793.0	ERP	9.2874	0.041	16.16	9M29D7W
NR Band n26	5 MHz	π/2 BPSK	816.5-821.5	Conducted	4.4886	0.347	25.40	4M49G7W
		QPSK	816.5-821.5	Conducted	4.4827	0.345	25.38	4M48G7W
		16QAM	816.5-821.5	Conducted	4.4745	0.271	24.33	4M47D7W
		64QAM	816.5-821.5	Conducted	4.4865	0.219	23.40	4M49D7W
		256QAM	816.5-821.5	Conducted	4.4784	0.111	20.45	4M48D7W
	10 MHz	π/2 BPSK	819.0	Conducted	8.9629	0.347	25.40	8M96G7W
		QPSK	819.0	Conducted	9.3099	0.336	25.26	9M31G7W
		16QAM	819.0	Conducted	9.3234	0.265	24.24	9M32D7W
		64QAM	819.0	Conducted	9.2838	0.218	23.38	9M28D7W
		256QAM	819.0	Conducted	9.2591	0.104	20.16	9M26D7W

EUT Overviews

Unless otherwise specified, no part of this report may be reproduced or utilized in any part, form or by any means, electronic or mechanical, including photocopying and microfilm, without permission in writing from Element Materials Technology. If you have any questions about this or have an enquiry about obtaining additional rights to this report or assembly of contents thereof, please contact ct.info@element.com.

1.0 INTRODUCTION

1.1 Scope

Measurement and determination of electromagnetic emissions (EMC) of radio frequency devices including intentional and/or unintentional radiators for compliance with the technical rules and regulations of the Federal Communications Commission and the Innovation, Science and Economic Development Canada.

1.2 Element Materials Technology Test Location

These measurement tests were conducted at the Element Materials Technology Morgan Hill facility located at 18855 Adams Court, Morgan Hill, CA 95037. The measurement facility is compliant with the test site requirements specified in ANSI C63.4-2014 and KDB 414788 D01 v01r01.

1.3 Test Facility / Accreditations

Measurements were performed at Element Materials Technology

- Element Materials Technology is an ISO 17025-2017 accredited test facility under the American Association for Laboratory Accreditation (A2LA) with Certificate number 2041.02 for Specific Absorption Rate (SAR), Hearing Aid Compatibility (HAC) testing, where applicable, and Electromagnetic Compatibility (EMC) testing for FCC and Innovation, Science, and Economic Development Canada rules.

- Element Washington DC LLC TCB is a Telecommunication Certification Body (TCB) accredited to ISO/IEC 17065-2012 by A2LA (Certificate number 2041.03) in all scopes of FCC Rules and ISED Standards (RSS).

- Element Materials Technology facility is a registered (22831) test laboratory with the site description on file with ISED.

- Element Washington DC LLC is a Recognized U.S. Certification Assessment Body (CAB # US0110) for ISED Canada as designated by NIST under the U.S. and Canada Mutual Agreements (MRAs).

Unless otherwise specified, no part of this report may be reproduced or utilized in any part, form or by any means, electronic or mechanical, including photocopying and microfilm, without permission in writing from Element Materials Technology. If you have any questions about this or have an enquiry about obtaining additional rights to this report or assembly of contents thereof, please contact ct.info@element.com.

2.0 PRODUCT INFORMATION

2.1 Equipment Description

The Equipment Under Test (EUT) is the **Apple Tablet Device FCC ID: BCGA2995**. The test data contained in this report pertains only to the emissions due to the EUT's licensed transmitters that operate under the provisions of Part 90.

Test Device Serial No.: WH6226Y7R5, D74GQ0GVJR, DVXJDXL1QN, H9HH5F000230000CFX

2.2 Device Capabilities

This device contains the following capabilities:

850/1700/1900 WCDMA/HSPA, Multi-band LTE, 5G NR (FR1), 802.11b/g/n/ax WLAN, 802.11a/n/ac/ax UNII, 802.11a/ax WIFI 6E, 802.15.4, Bluetooth (1x, EDR, LE1M, LE2M, HDR4, HDR8), NB UNII (1x, HDR4, HDR8), WPT

This device supports BT Beamforming

This device supports simultaneous transmission operations, which allows for multiple transmitters to transmit simultaneously on the same antenna. The table below shows all configurations possible.

Antenna	Simultaneous Tx Config	Bluetooth 2.4GHz	Thread	NB UNII	WLAN	WIFI 5GHz	WIFI 6GHz	LTE / FR1 NR		
		BDR, EDR, HDR4/8, LE1/2M	802.15.4	BDR, HDR4/8	802.11 b/g/n/ax	802.11 a/n/ac/ax	802.11 a/ax	LB	MB/HB	Ultra High Band
1a	Config 1	✓	×	×	×	×	×	×	×	✓
1a	Config 2	×	×	×	✓	×	×	×	×	✓
1a	Config 3	×	✓	×	×	×	×	×	×	✓
1b	Config 4	×	×	✓	×	×	×	×	✓	×
1b	Config 5	×	×	×	×	✓	×	×	✓	×
1b	Config 6	×	×	×	×	×	✓	×	✓	×
3a	Config 7	×	×	×	✓	×	×	×	×	✓
3a	Config 8	✓	×	×	×	×	×	×	×	✓
3a	Config 9	×	✓	×	×	×	×	×	×	✓
3b	Config 10	×	×	✓	×	×	×	×	✓	×
3b	Config 11	×	×	×	×	✓	×	×	✓	×
3b	Config 12	×	×	×	×	×	✓	×	✓	×
4	Config 13	✓	×	×	×	×	×	✓	×	×
4	Config 14	✓	×	×	×	×	×	×	✓	×
4	Config 15	✓	×	×	×	×	×	×	×	✓
4	Config 16	×	✓	×	×	×	×	✓	×	×
4	Config 17	×	✓	×	×	×	×	×	✓	×
4	Config 18	×	✓	×	×	×	×	×	×	✓

Table 2-1. Simultaneous Transmission Configurations

✓ = Support; × = Not Support

Unless otherwise specified, no part of this report may be reproduced or utilized in any part, form or by any means, electronic or mechanical, including photocopying and microfilm, without permission in writing from Element Materials Technology. If you have any questions about this or have an enquiry about obtaining additional rights to this report or assembly of contents thereof, please contact ct.info@element.com.

Note:

1. All the above simultaneous transmission configurations have been tested and the worst case configuration was found to be Config 14 and reported in RF Bluetooth and RF FCC Part 27b test reports.

2. Specific 2.4GHz Wi-Fi antenna that can only transmit simultaneously with 2.4GHz Bluetooth antenna is listed in the SAR test report. For BT (2.4GHz), in both connected and disconnected modes, and Wi-Fi (2.4GHz) - Wi-Fi max power will not exceed minimum of (13.5dBm, SAR max cap, Reg max cap) power. Bluetooth can simultaneously transmit with IEEE 802.11a/n/ac/ax 5/6 GHz on separate antenna.

2.3 Antenna Description

Following antenna gains provided by manufacturer were used for testing.

Band	Antenna Gain [dBi]	
	Antenna 4	Antenna 2
LTE Band 14	-2.1	-3.3
NR Band n14		
LTE Band 26	-1.8	-2.4
NR Band n26		

Table 2-2. Highest Antenna Gain

2.4 Test Support Equipment

1	Apple MacBook Pro	Model:	A2141	S/N:	C02H604EQ05D
	w/AC/DC Adapter	Model:	A2166	S/N:	C4H042705ZNPM0WA6
2	Apple USB-C Cable	Model:	Spartan	S/N:	GXK1336018XKTR024
3	USB-C Cable	Model:	A246C	S/N:	DWH80115BK826GV19
	w/ AC Adapter	Model:	A2305	S/N:	C4H95160004PF4F4V
4	Apple Pencil	Model:	A2538	S/N:	KJ26TCFXJW
5	DC Power Supply	Model:	KPS3010D	S/N:	N/A

Table 2-3. Test Support Equipment

Unless otherwise specified, no part of this report may be reproduced or utilized in any part, form or by any means, electronic or mechanical, including photocopying and microfilm, without permission in writing from Element Materials Technology. If you have any questions about this or have an enquiry about obtaining additional rights to this report or assembly of contents thereof, please contact ct.info@element.com.

2.5 Test Configuration

The EUT was tested per the guidance of ANSI C63.26-2015 and KDB 971168 D01 v03r01. See Section 7.0 of this test report for a description of the radiated and antenna port conducted emissions tests.

For emissions from 1GHz – 18GHz, low, mid, and high channels were tested with highest power and worst case configuration. The emissions below 1GHz were tested with the highest transmitting power and the worst case channel.

The EUT was manipulated through three orthogonal planes of X-orientation (flatbed), Y-orientation (landscape), and Z-orientation (portrait) during the testing. Only the worst case emissions were reported in this test report.

2.6 Software and Firmware

The test was conducted with firmware version 22A312 installed on the EUT.

2.7 EMI Suppression Device(s)/Modifications

No EMI suppression device(s) were added and no modifications were made during testing.

Unless otherwise specified, no part of this report may be reproduced or utilized in any part, form or by any means, electronic or mechanical, including photocopying and microfilm, without permission in writing from Element Materials Technology. If you have any questions about this or have an enquiry about obtaining additional rights to this report or assembly of contents thereof, please contact ct.info@element.com.

3.0 DESCRIPTION OF TESTS

3.1 Evaluation Procedure

The measurement procedures described in the documents titled "American National Standard for Compliance Testing of Transmitters Used in Licensed Radio Services" (ANSI C63.26-2015 and "Procedures for Compliance Measurement of the Fundamental Emission Power of Licensed Wideband (> 1 MHz) Digital Transmission Systems" (KDB 971168 D01 v03r01) were used in the measurement of the EUT.

Deviation from Measurement Procedure……...None

3.2 Radiated Spurious Emissions

The radiated test facilities consisted of an indoor 3 meter semi-anechoic chamber used for final measurements and exploratory measurements, when necessary. The measurement area is contained within the semi-anechoic chamber which is shielded from any ambient interference. The test site inside the chamber is a 6m x 5.2m elliptical, obstruction-free area in accordance with Figure 5.7 of Clause 5 in ANSI C63.4-2014. Absorbers are arranged on the floor between the turn table and the antenna mast in such a way so as to maximize the reduction of reflections for measurements above 1GHz. For measurements below 1GHz, the absorbers are removed. A raised turntable is used for radiated measurement. The turn table is a continuously rotatable, remote-controlled, metallic turntable and 2 meters (6.56 ft.) in diameter. The turn table is flush with the raised floor of the chamber in order to maintain its function as a ground plane. An 80cm tall test table made of Styrodur is placed on top of the turn table. A Styrodur pedestal is placed on top of the test table to bring the total table height to 1.5m.

The equipment under test was transmitting while connected to its integral antenna and is placed on a turntable 3 meters from the receive antenna. The receive antenna height is adjusted between 1 and 4 meter height, the turntable is rotated through 360 degrees, and the EUT is manipulated through all orthogonal planes representative of its typical use to achieve the highest reading on the receive spectrum analyzer.

For radiated spurious emissions measurements and calculations, conversion method is used per the formulas in KDB 971168 Section 5.8.4. Field Strength (EIRP) is calculated using the following formulas:

$$E_{[dB\mu V/m]} = \text{Measured amplitude level}_{[dBm]} + 107 + \text{Cable Loss}_{[dB]} + \text{Antenna Factor}_{[dB/m]}$$

And

$$EIRP_{[dBm]} = E_{[dB\mu V/m]} + 20\log D - 104.8;$$ where D is the measurement distance in meters.

All radiated measurements are performed in a chamber that meets the site requirements per ANSI C63.4-2014.

Per KDB 414788 D01 v01r01, radiated emission test sites other than open-field test sites (e.g., shielded anechoic chambers), may be employed for emission measurements below 30MHz if characterized so that the measurements correspond to those obtained at an open-field test site. To determine test site equivalency, a reference sample transmitting at 149kHz was measured on an open field test site (asphalt with no ground plane) and then measured in the 3m semi-anechoic chamber. A calibrated 60cm loop antenna was used while the reference device was rotated through the X, Y and Z axis in order to capture the worst case level. A maximum deviation of 2.77dB at 149kHz was measured when comparing the 3 meter semi-anechoic chamber to the open field site.

Radiated spurious emission levels are investigated with the receive antenna horizontally and vertically polarized per ANSI C63.26-2015.

Unless otherwise specified, no part of this report may be reproduced or utilized in any part, form or by any means, electronic or mechanical, including photocopying and microfilm, without permission in writing from Element Materials Technology. If you have any questions about this or have an enquiry about obtaining additional rights to this report or assembly of contents thereof, please contact ct.info@element.com.

4.0 MEASUREMENT UNCERTAINTY

The measurement uncertainties shown below were calculated in accordance with the requirements of ANSI C63.23-2012. All measurement uncertainty values are shown with a coverage factor of k = 2 to indicate a 95% level of confidence. The measurement uncertainty shown below meets or exceeds the U_{CISPR} measurement uncertainty values specified in CISPR 16-4-2 and, thus, can be compared directly to specified limits to determine compliance.

Contribution	Expanded Uncertainty (±dB)
Conducted Bench Top Measurements	2.07
Radiated Disturbance (<30MHz)	4.12
Radiated Disturbance (30MHz-1GHz)	4.85
Radiated Disturbance (1-18GHz)	5.08

Unless otherwise specified, no part of this report may be reproduced or utilized in any part, form or by any means, electronic or mechanical, including photocopying and microfilm, without permission in writing from Element Materials Technology. If you have any questions about this or have an enquiry about obtaining additional rights to this report or assembly of contents thereof, please contact ct.info@element.com.

5.0 TEST EQUIPMENT CALIBRATION DATA

Test Equipment Calibration is traceable to the National Institute of Standards and Technology (NIST). Measurements antennas used during testing were calibrated in accordance to the requirements of ANSI C63.5-2017.

Manufacturer	Model	Description	Cal Date	Cal Interval	Cal Due	Serial Number
Rohde & Schwarz	FSW67	Signal and Spectrum Analyzer (2Hz-67GHz)	7/5/2024	Annual	7/5/2025	101366
ATM	180-442A-KF	20dB Nominal Gain Horn Antenna	3/14/2024	Annual	3/14/2025	T058701-01
ESPEC	SU-241	Tabletop Temperature Chamber	11/17/2023	Annual	11/17/2024	92009574
ETS-Lindgren	3117	Double Ridged Guide Antenna (1-18 GHz)	4/9/2024	Annual	4/9/2025	00218555
Fairview Microwave	FMCA1975-36	30MHz-40GHz Conducted Cable *	6/10/2024	Annual	6/10/2025	-
Fairview Microwave	M2CP1122-10	30MHz-40GHz Conducted Coupler *	6/10/2024	Annual	6/10/2025	1946
Keysight Technology	N9040B	UXA Signal Analyzer	5/28/2024	Annual	5/28/2025	MY57212015
Rohde & Schwarz	TS-PR18	Pre-Amplifier (1GHz - 18GHz)	8/15/2023	Annual	8/15/2024	101639
Rohde & Schwarz	FSV40	Signal Analyzer (10Hz-40GHz)	5/29/2024	Annual	5/29/2025	101619
Rohde & Schwarz	ESW44	EMI Test Receiver	5/1/2024	Annual	5/1/2025	101867
Rohde & Schwarz	TS-PR8	Pre-Amplifier (30MHz - 8GHz)	7/3/2024	Annual	7/3/2025	102356
Rohde & Schwarz	CMW500	Wideband Radio Communication Tester	11/30/2023	Annual	11/30/2024	161616
Rohde & Schwarz	CMW500	Wideband Radio Communication Tester	12/27/2023	Annual	12/27/2024	164715
Rohde & Schwarz	TS-PR1840	Pre-Amplifier (18GHz - 40GHz)	6/10/2024	Annual	6/10/2025	100057
Rohde & Schwarz	HFH2-Z2	Loop Antenna	6/21/2024	Annual	6/21/2025	100519
Rohde & Schwarz	ENV216	Two-Line V-Network	4/24/2024	Annual	4/24/2025	101364
Schwarzbeck	VULB 9162	Bilog Antenna (30MHz - 6GHz)	4/29/2024	Annual	4/29/2025	00304

Table 5-1. Test Equipment List

Notes:

1. For equipment listed above that has a calibration date or calibration due date that falls within the test date range, care was taken to ensure that this equipment was used after the calibration date and before the calibration due date.
2. * Denotes passive equipment that have been internally verified/calibrated.

Unless otherwise specified, no part of this report may be reproduced or utilized in any part, form or by any means, electronic or mechanical, including photocopying and microfilm, without permission in writing from Element Materials Technology. If you have any questions about this or have an enquiry about obtaining additional rights to this report or assembly of contents thereof, please contact ct.info@element.com.

6.0 SAMPLE CALCULATIONS

Emission Designator

π/2 BPSK / QPSK Modulation

Emission Designator = 8M62G7W
BW = 8.62 MHz
G = Phase Modulation
7 = Quantized/Digital Info
W = Combination of Any

QAM Modulation

Emission Designator = 8M45D7W
BW = 8.45 MHz
D = Amplitude/Angle Modulated
7 = Quantized/Digital Info
W = Combination of Any

Spurious Radiated Emission

Example: Spurious emission at 3700.40 MHz

The receive spectrum analyzer reading at 3 meters with the EUT on the turntable was –81.0 dBm. The gain of the substituted antenna is 8.1 dBi. The signal generator connected to the substituted antenna terminals is adjusted to produce a reading of –81.0 dBm on the spectrum analyzer. The loss of the cable between the signal generator and the terminals of the substituted antenna is 2.0 dB at 3700.40 MHz. So 6.1 dB is added to the signal generator reading of –30.9 dBm yielding –24.80 dBm. The fundamental EIRP was 25.50 dBm so this harmonic was 25.50 dBm – (-24.80) = 50.3 dBc.

Unless otherwise specified, no part of this report may be reproduced or utilized in any part, form or by any means, electronic or mechanical, including photocopying and microfilm, without permission in writing from Element Materials Technology. If you have any questions about this or have an enquiry about obtaining additional rights to this report or assembly of contents thereof, please contact ct.info@element.com.

7.0 TEST RESULTS

7.1 Summary

Company Name: Apple Inc.

FCC ID: BCGA2995

FCC Classification: PCS Licensed Transmitter (PCB)

Mode(s): LTE/NR

Test Condition	Test Description	FCC Part Section(s)	Test Limit	Test Result	Reference
CONDUCTED	Occupied Bandwidth	2.1049	N/A	N/A	Section 7.2
	Conducted Band Edge / Spurious Emissions (LTE Band 14)	2.1051, 90.543(e)	On all frequencies between 769-775 MHz and 799-805 MHz, attenuation by a factor not less than 65 + 10 log(P) dB in a 6.25 kHz band segment, for mobile and portable stations. On any frequency between 775-788 MHz, above 805 MHz, and below 758 MHz, attenuation by at least 43 + 10 log(P) dB	PASS	Sections 7.3, 7.4
	Conducted Band Edge / Spurious Emissions (NR Band n14)				
	Conducted Band Edge / Spurious Emissions (LTE Band 26)	2.1051, 90.691(a)	-13 dBm for all out-of-band emissions except -30 dBm at Band Edge and for all out-of-band emissions within 37.5kHz of Block Edge	PASS	Sections 7.3, 7.4
	Conducted Band Edge / Spurious Emissions (CDMA BC10)			PASS	Sections 7.3, 7.4
	Frequency Stability (LTE Band 14)	2.1055	Fundamental emissions stay within authorized frequency block over the temperature and voltage range as tested.	PASS	Section 7.8
	Frequency Stability (LTE Band 26)	90.213	< 2.5 ppm	PASS	Section 7.8
	Conducted Power	2.1046, 90.635	< 100 Watts	PASS	Section 7.5
	Effective Radiated Power (LTE Band 14)	90.542(a)(7)	< 3 Watts max. ERP	PASS	Section 7.6
	Effective Radiated Power (NR Band n14)			PASS	Section 7.6
	Effective Radiated Power (LTE Band 26)	22.913(a)(5)	< 7 Watts max. ERP	PASS	Section 7.6
	Effective Radiated Power (CDMA BC10)			PASS	Section 7.6
RADIATED	Radiated Spurious Emissions (LTE Band 14)	2.1053, 90.543(e)	> 43 + 10 log10 (P[Watts]) for all out-of-band emissions except emissions in the 1559 - 1610MHz band are subject to a limit of -40dBm/MHz for wideband signals	PASS	Section 7.7
	Radiated Spurious Emissions (NR Band n14)			PASS	Section 7.7
	Radiated Spurious Emissions (LTE Band 26)	2.1053, 90.691(a)	-13 dBm for all out-of-band emissions except -30 dBm at Band Edge and for all out-of-band emissions within 37.5kHz of Block Edge	PASS	Section 7.7
	Radiated Spurious Emissions (CDMA BC10)			PASS	Section 7.7

Table 7-1. Summary of Test Results

Unless otherwise specified, no part of this report may be reproduced or utilized in any part, form or by any means, electronic or mechanical, including photocopying and microfilm, without permission in writing from Element Materials Technology. If you have any questions about this or have an enquiry about obtaining additional rights to this report or assembly of contents thereof, please contact ct.info@element.com.

Notes:

1. All modes of operation and data rates were investigated. The test results shown in the following sections represent the worst case emissions.

2. The analyzer plots shown in Section 7.0 were taken with a correction table loaded into the analyzer. The correction table was used to account for the losses of the cables, directional couplers, and attenuators used as part of the system to maintain a link between the call box and the EUT at all frequencies of interest.

3. All antenna port conducted emissions testing was performed on a test bench with the antenna port of the EUT connected to the spectrum analyzer through calibrated cables, attenuators, and couplers.

4. For conducted spurious emissions, automated test software was used to measure emissions and capture the corresponding plots necessary to show compliance. The measurement software utilized is Element EMC Software Tool v1.1.

5. For radiated spurious emissions, automated test software was used to measure emissions and capture the corresponding plots necessary to show compliance. The measurement software's utilized are Element "Chamber Automation," Version 3.0.0.

6. All ports were investigated and for some test cases only the worst case data was reported.

Unless otherwise specified, no part of this report may be reproduced or utilized in any part, form or by any means, electronic or mechanical, including photocopying and microfilm, without permission in writing from Element Materials Technology. If you have any questions about this or have an enquiry about obtaining additional rights to this report or assembly of contents thereof, please contact ct.info@element.com.

7.2 Occupied Bandwidth

§2.1049

Test Overview

The occupied bandwidth, that is the frequency bandwidth such that, below its lower and above its upper frequency limits, the mean powers radiated are each equal to 0.5 percent of the total mean power radiated by a given emission shall be measured. All modes of operation and all ports were investigated and the worst case configuration results are reported in this section.

Test Procedure Used

KDB 971168 D01 v03r01 – Section 4.2

Test Settings

1. The signal analyzer's automatic bandwidth measurement capability was used to perform the 99% occupied bandwidth and the 26dB bandwidth. The bandwidth measurement was not influenced by any intermediate power nulls in the fundamental emission.
2. RBW = 1 – 5% of the expected OBW
3. VBW ≥ 3 x RBW
4. Detector = Peak
5. Trace mode = max hold
6. Sweep = auto couple
7. The trace was allowed to stabilize
8. If necessary, steps 2 – 7 were repeated after changing the RBW such that it would be within 1 – 5% of the 99% occupied bandwidth observed in Step 7

Unless otherwise specified, no part of this report may be reproduced or utilized in any part, form or by any means, electronic or mechanical, including photocopying and microfilm, without permission in writing from Element Materials Technology. If you have any questions about this or have an enquiry about obtaining additional rights to this report or assembly of contents thereof, please contact ct.info@element.com.

Test Setup

The EUT and measurement equipment were set up as shown in the diagram below.

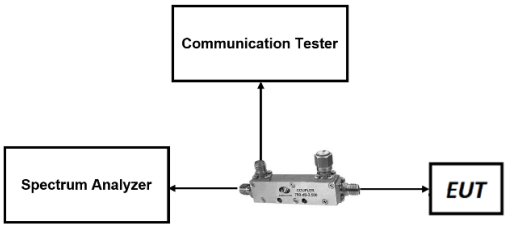


Figure 7-1. LTE Test Instrument & Measurement Setup

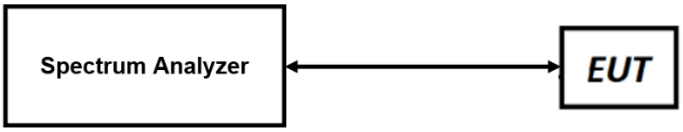


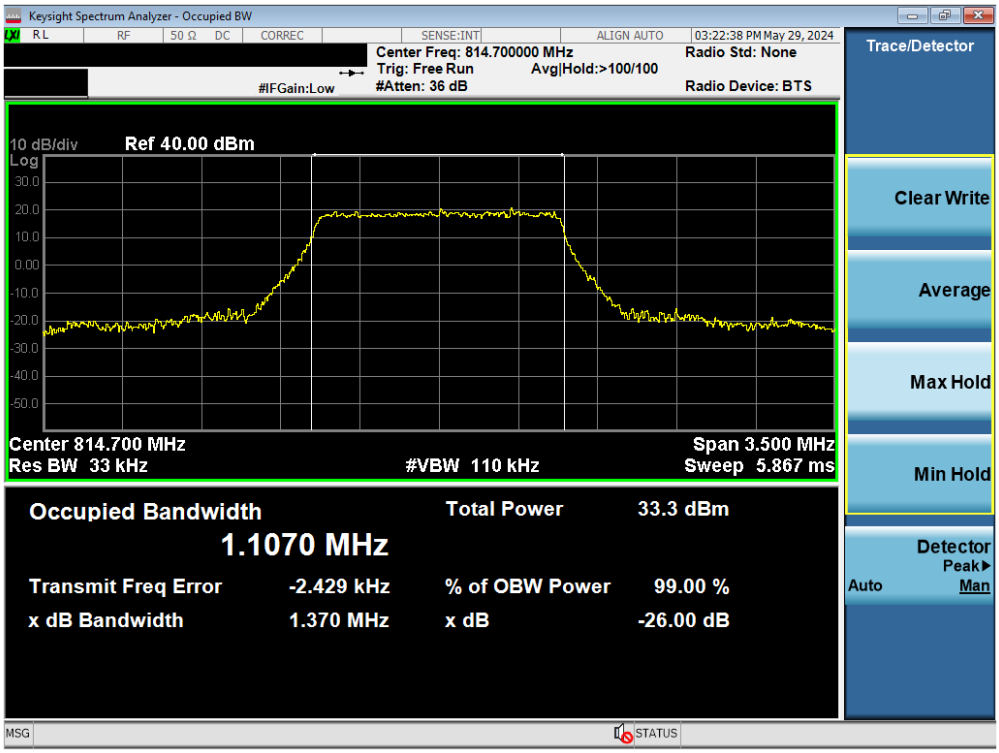
Figure 7-2. FR1 Test Instrument & Measurement Setup

Test Notes

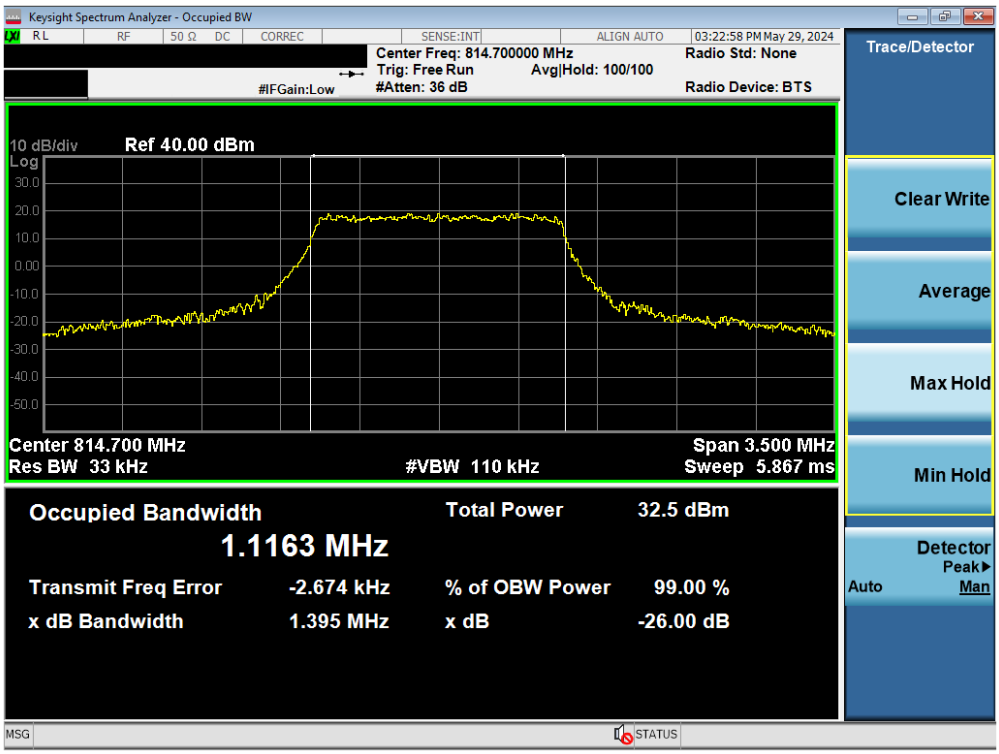
None.

Unless otherwise specified, no part of this report may be reproduced or utilized in any part, form or by any means, electronic or mechanical, including photocopying and microfilm, without permission in writing from Element Materials Technology. If you have any questions about this or have an enquiry about obtaining additional rights to this report or assembly of contents thereof, please contact ct.info@element.com.

LTE Band 26

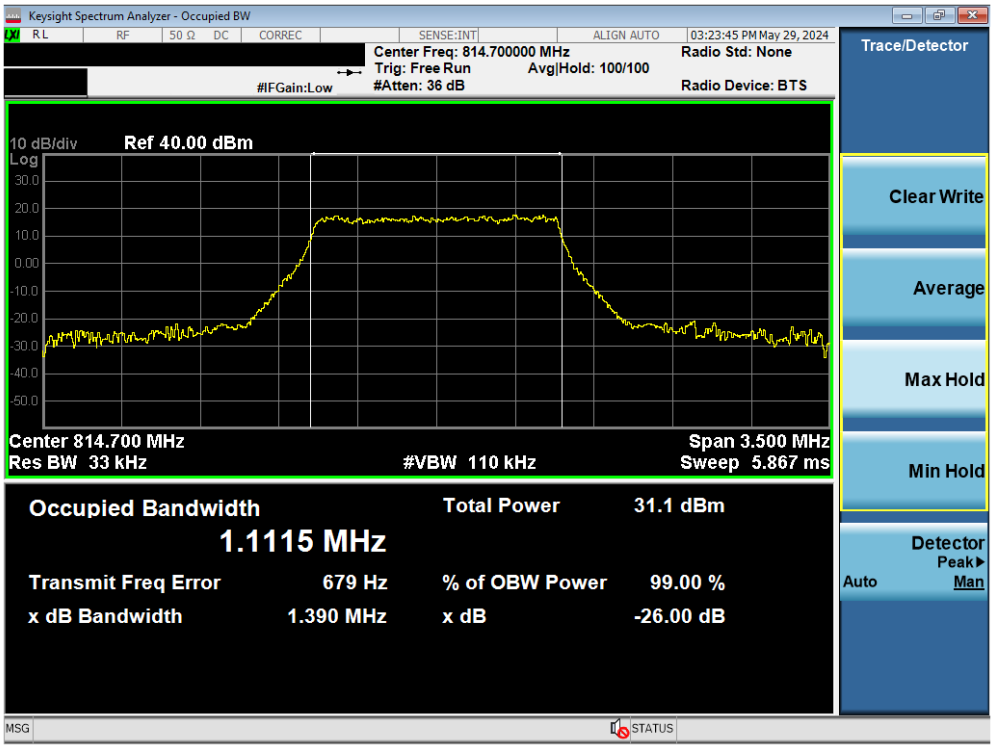


Plot 7-1. Occupied Bandwidth Plot (LTE Band 26 - 1.4MHz QPSK - Full RB)

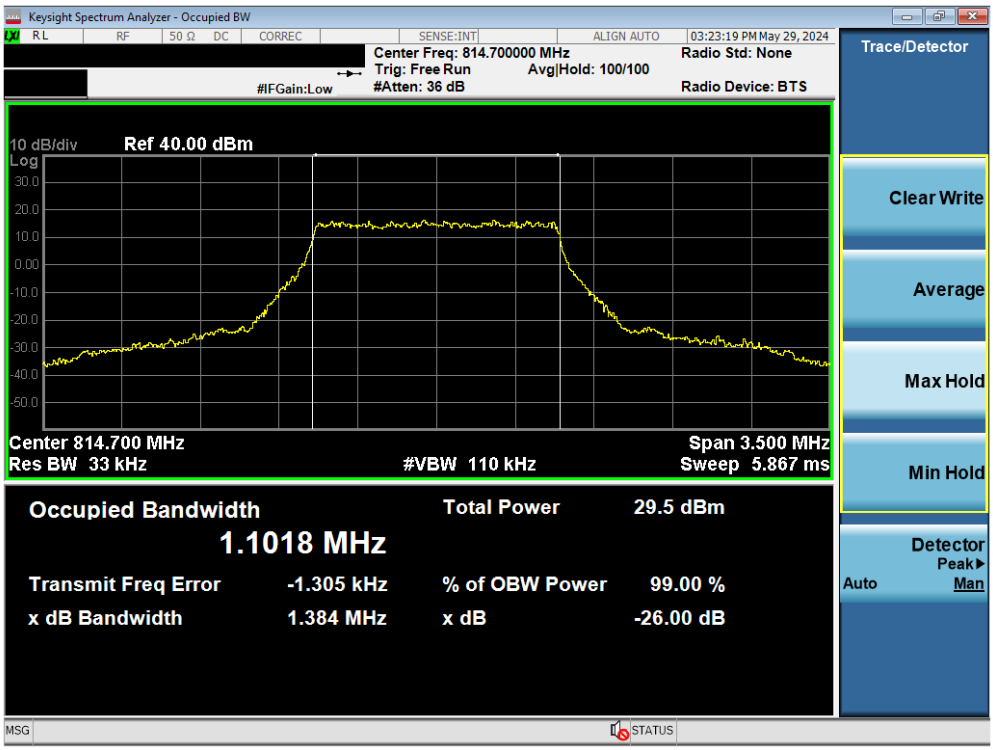


Plot 7-2. Occupied Bandwidth Plot (LTE Band 26 - 1.4MHz 16-QAM - Full RB)

Unless otherwise specified, no part of this report may be reproduced or utilized in any part, form or by any means, electronic or mechanical, including photocopying and microfilm, without permission in writing from Element Materials Technology. If you have any questions about this or have an enquiry about obtaining additional rights to this report or assembly of contents thereof, please contact ct.info@element.com.

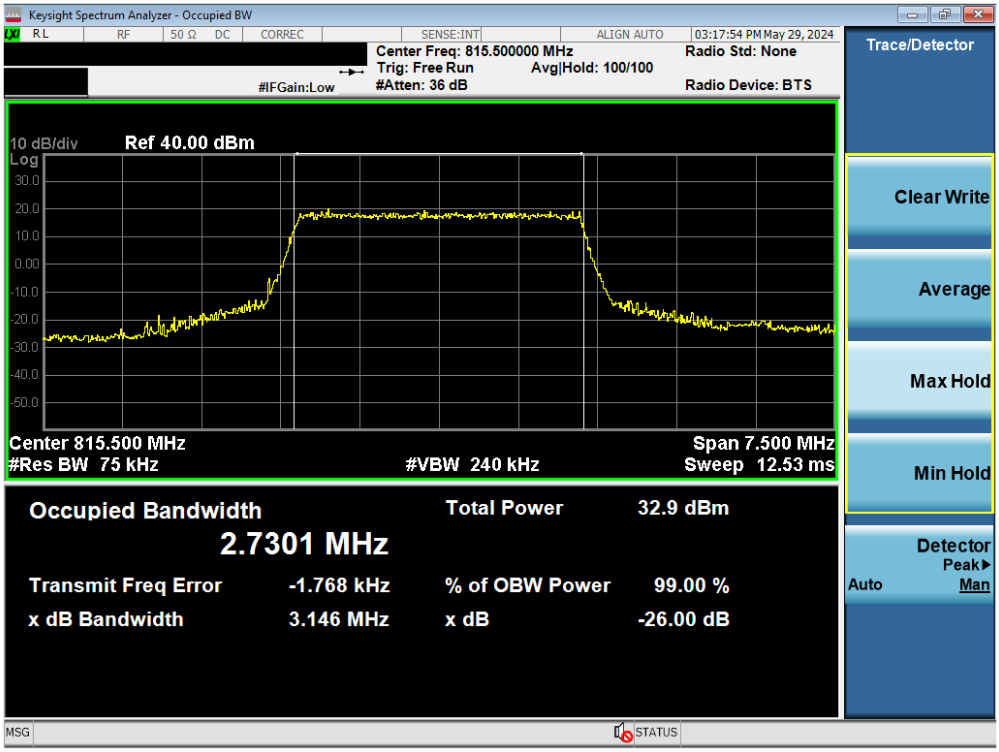


Plot 7-3. Occupied Bandwidth Plot (LTE Band 26 - 1.4MHz 64-QAM - Full RB)

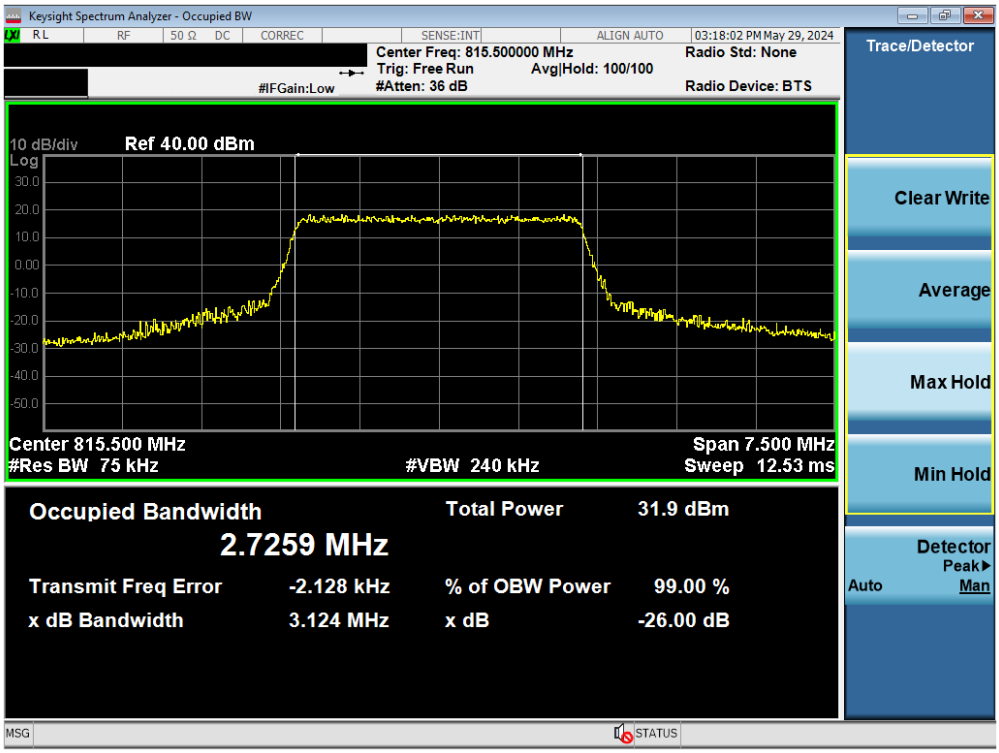


Plot 7-4. Occupied Bandwidth Plot (LTE Band 26 - 1.4MHz 256-QAM - Full RB)

Unless otherwise specified, no part of this report may be reproduced or utilized in any part, form or by any means, electronic or mechanical, including photocopying and microfilm, without permission in writing from Element Materials Technology. If you have any questions about this or have an enquiry about obtaining additional rights to this report or assembly of contents thereof, please contact ct.info@element.com.



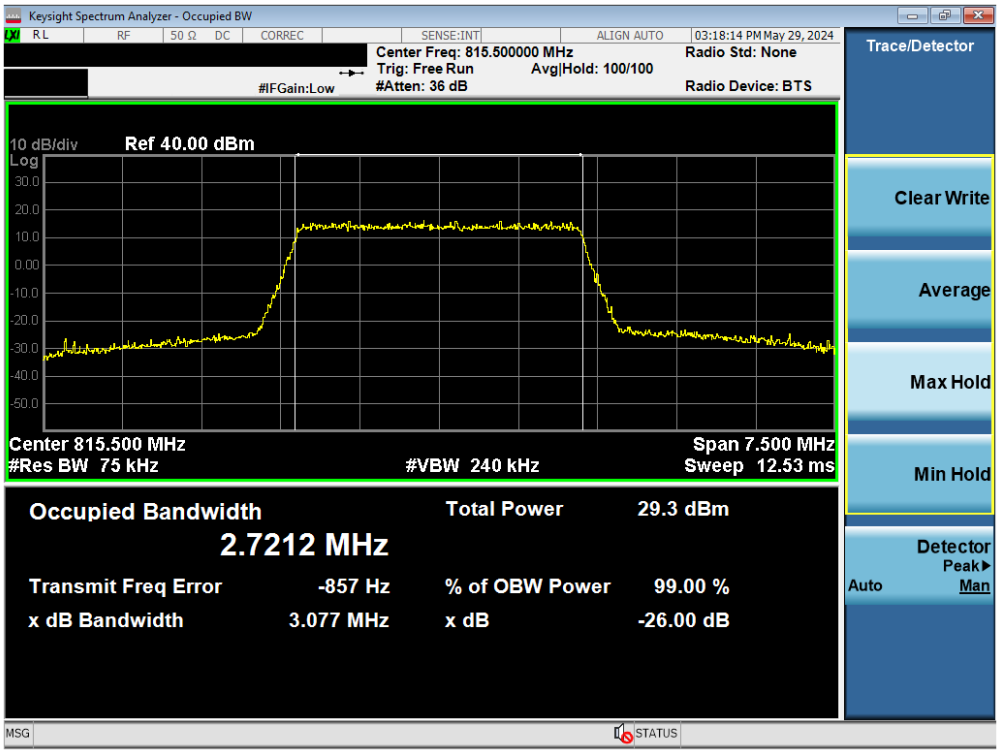
Plot 7-5. Occupied Bandwidth Plot (LTE Band 26 - 3MHz QPSK - Full RB)



Plot 7-6. Occupied Bandwidth Plot (LTE Band 26 - 3MHz 16-QAM - Full RB)

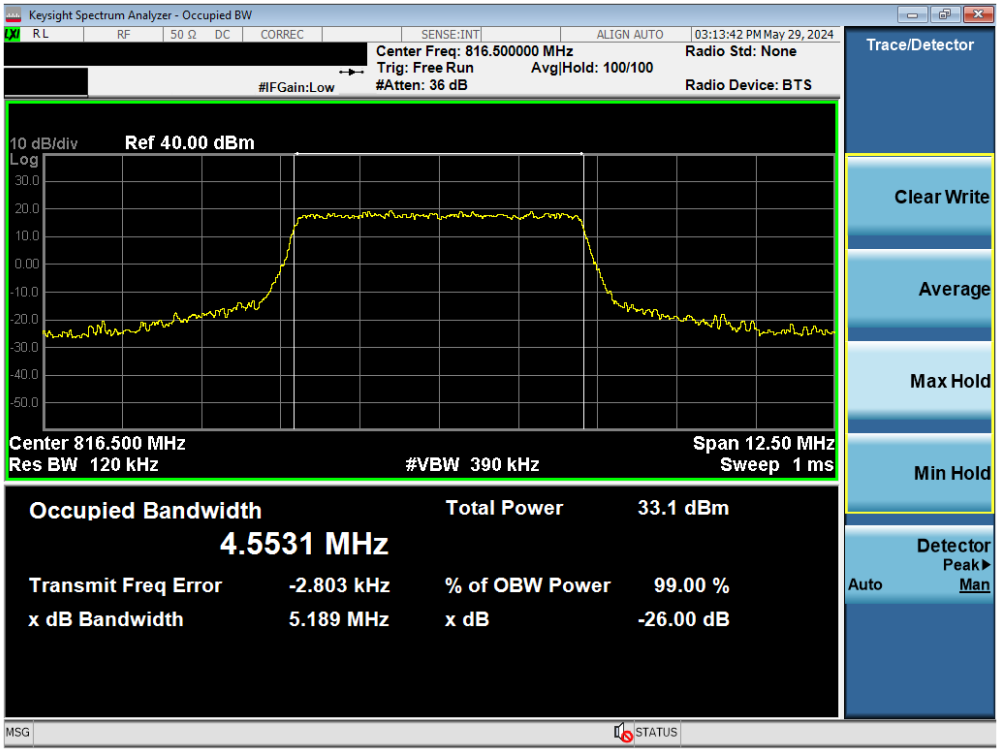
Unless otherwise specified, no part of this report may be reproduced or utilized in any part, form or by any means, electronic or mechanical, including photocopying and microfilm, without permission in writing from Element Materials Technology. If you have any questions about this or have an enquiry about obtaining additional rights to this report or assembly of contents thereof, please contact ct.info@element.com.

Plot 7-7. Occupied Bandwidth Plot (LTE Band 26 - 3MHz 64-QAM - Full RB)

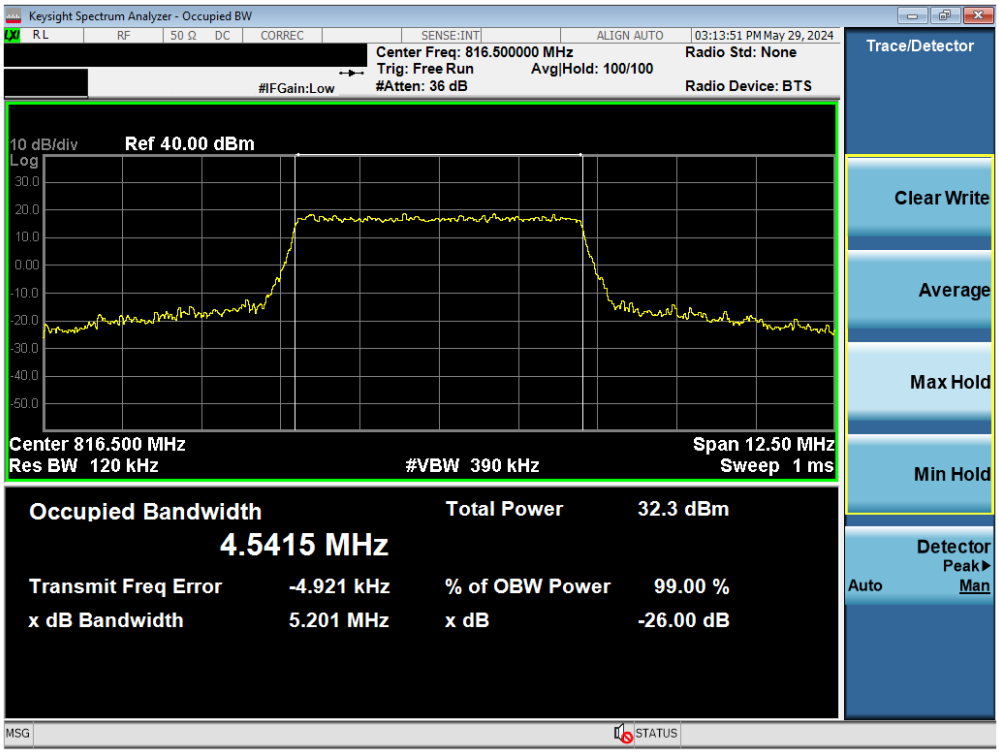


Plot 7-8. Occupied Bandwidth Plot (LTE Band 26 - 3MHz 256-QAM - Full RB)

Unless otherwise specified, no part of this report may be reproduced or utilized in any part, form or by any means, electronic or mechanical, including photocopying and microfilm, without permission in writing from Element Materials Technology. If you have any questions about this or have an enquiry about obtaining additional rights to this report or assembly of contents thereof, please contact ct.info@element.com.



Plot 7-9. Occupied Bandwidth Plot (LTE Band 26 - 5MHz QPSK - Full RB)



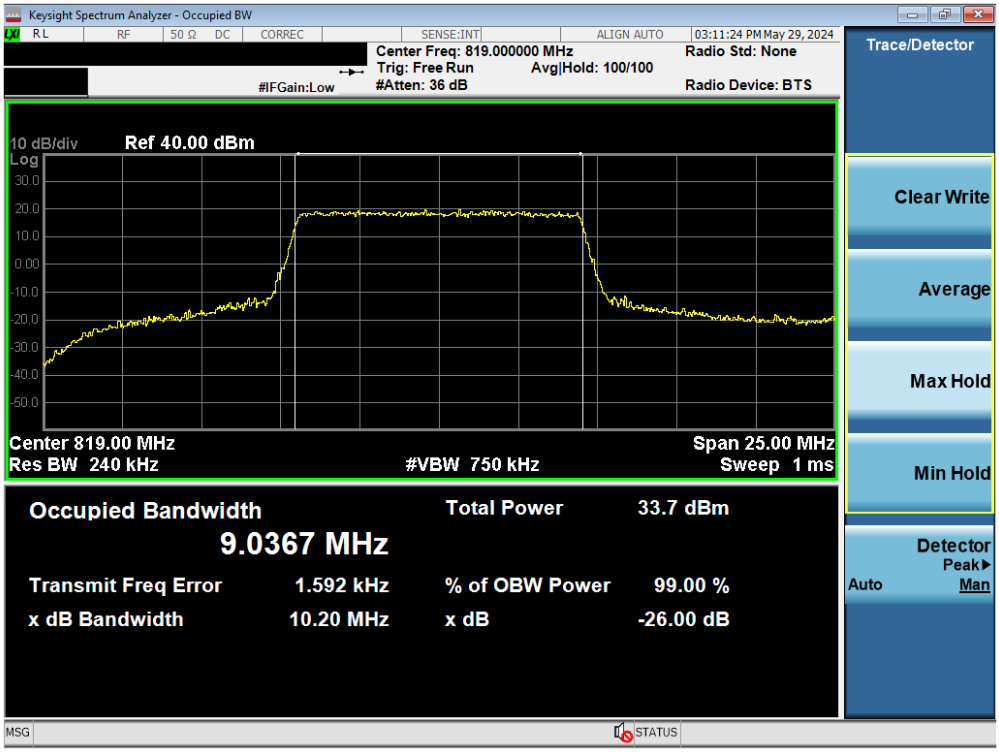
Plot 7-10. Occupied Bandwidth Plot (LTE Band 26 - 5MHz 16-QAM - Full RB)

Unless otherwise specified, no part of this report may be reproduced or utilized in any part, form or by any means, electronic or mechanical, including photocopying and microfilm, without permission in writing from Element Materials Technology. If you have any questions about this or have an enquiry about obtaining additional rights to this report or assembly of contents thereof, please contact ct.info@element.com.

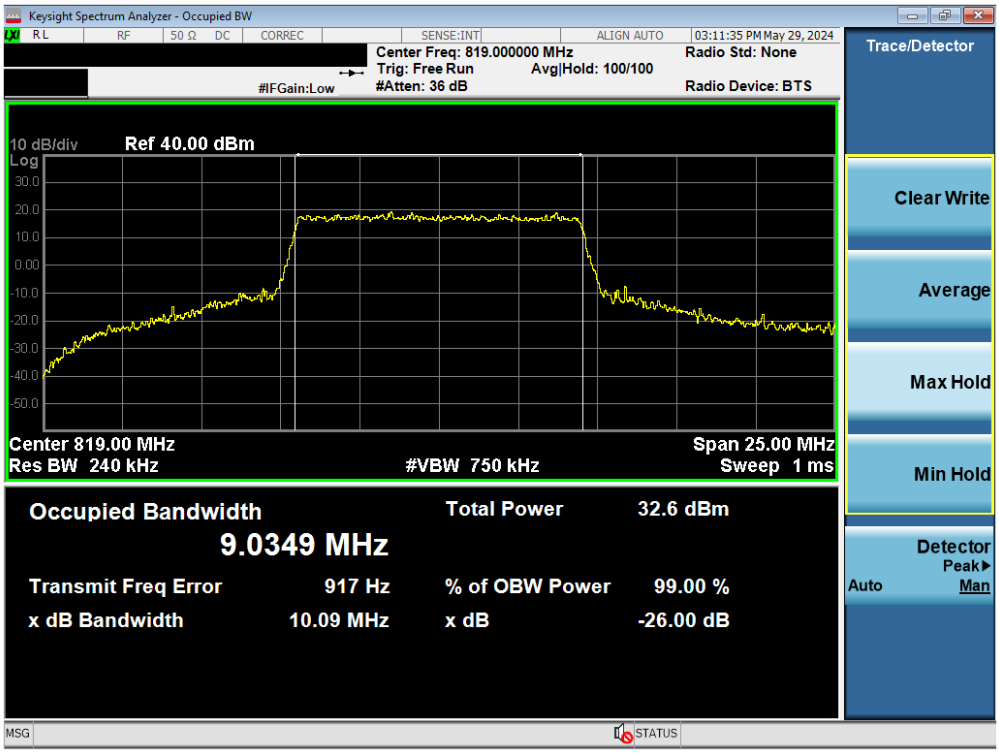
Plot 7-11. Occupied Bandwidth Plot (LTE Band 26 - 5MHz 64-QAM - Full RB)

Plot 7-12. Occupied Bandwidth Plot (LTE Band 26 - 5MHz 256-QAM - Full RB)

Unless otherwise specified, no part of this report may be reproduced or utilized in any part, form or by any means, electronic or mechanical, including photocopying and microfilm, without permission in writing from Element Materials Technology. If you have any questions about this or have an enquiry about obtaining additional rights to this report or assembly of contents thereof, please contact ct.info@element.com.

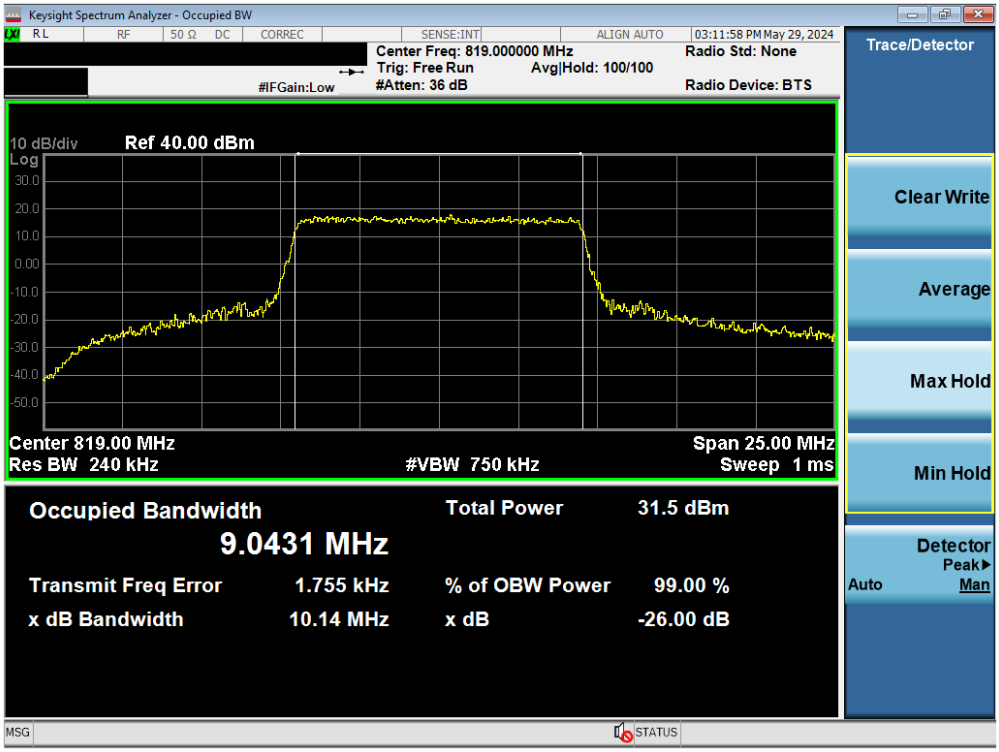


Plot 7-13. Occupied Bandwidth Plot (LTE Band 26 - 10MHz QPSK - Full RB)



Plot 7-14. Occupied Bandwidth Plot (LTE Band 26 - 10MHz 16-QAM - Full RB)

Unless otherwise specified, no part of this report may be reproduced or utilized in any part, form or by any means, electronic or mechanical, including photocopying and microfilm, without permission in writing from Element Materials Technology. If you have any questions about this or have an enquiry about obtaining additional rights to this report or assembly of contents thereof, please contact ct.info@element.com.

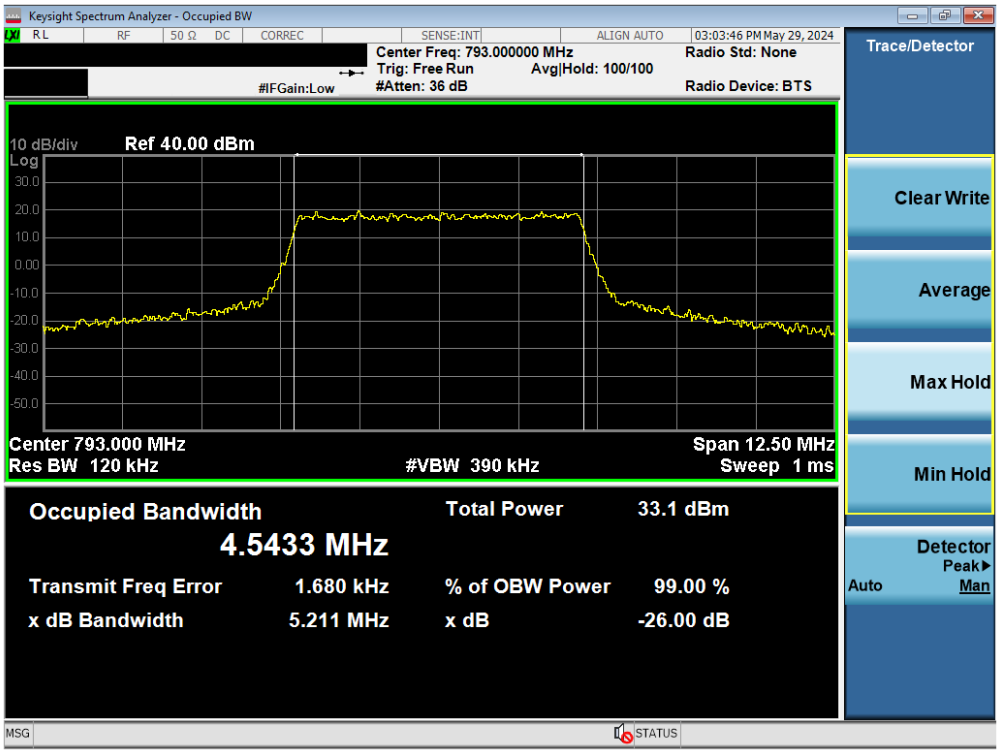


Plot 7-15. Occupied Bandwidth Plot (LTE Band 26 - 10MHz 64-QAM - Full RB)

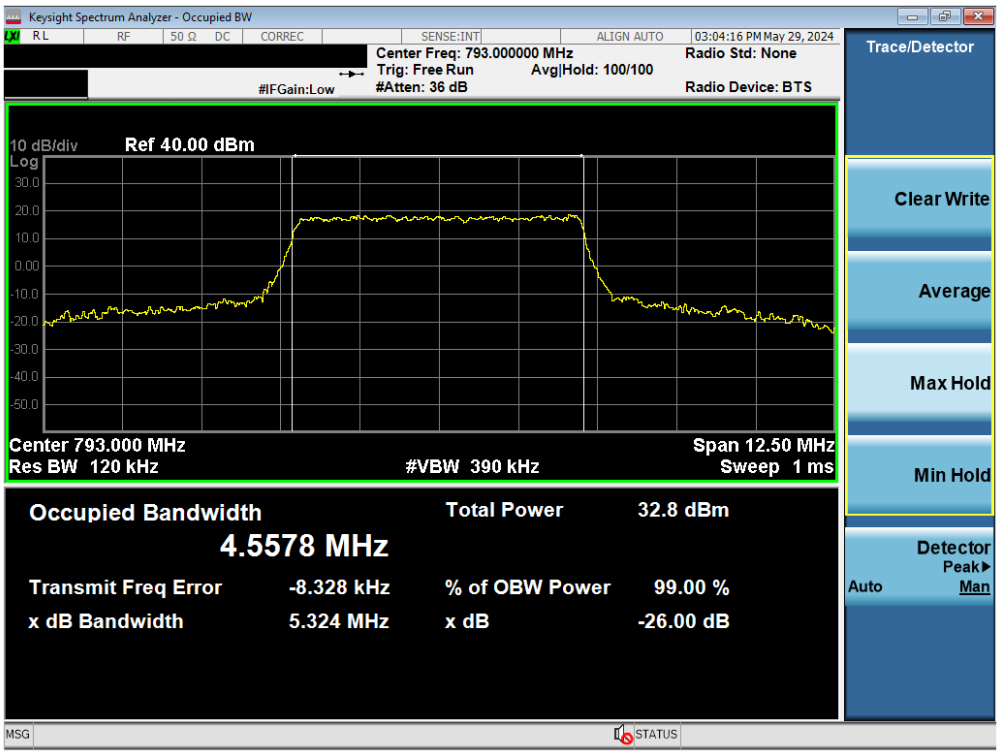
Plot 7-16. Occupied Bandwidth Plot (LTE Band 26 - 10MHz 256-QAM - Full RB)

Unless otherwise specified, no part of this report may be reproduced or utilized in any part, form or by any means, electronic or mechanical, including photocopying and microfilm, without permission in writing from Element Materials Technology. If you have any questions about this or have an enquiry about obtaining additional rights to this report or assembly of contents thereof, please contact ct.info@element.com.

LTE Band 14

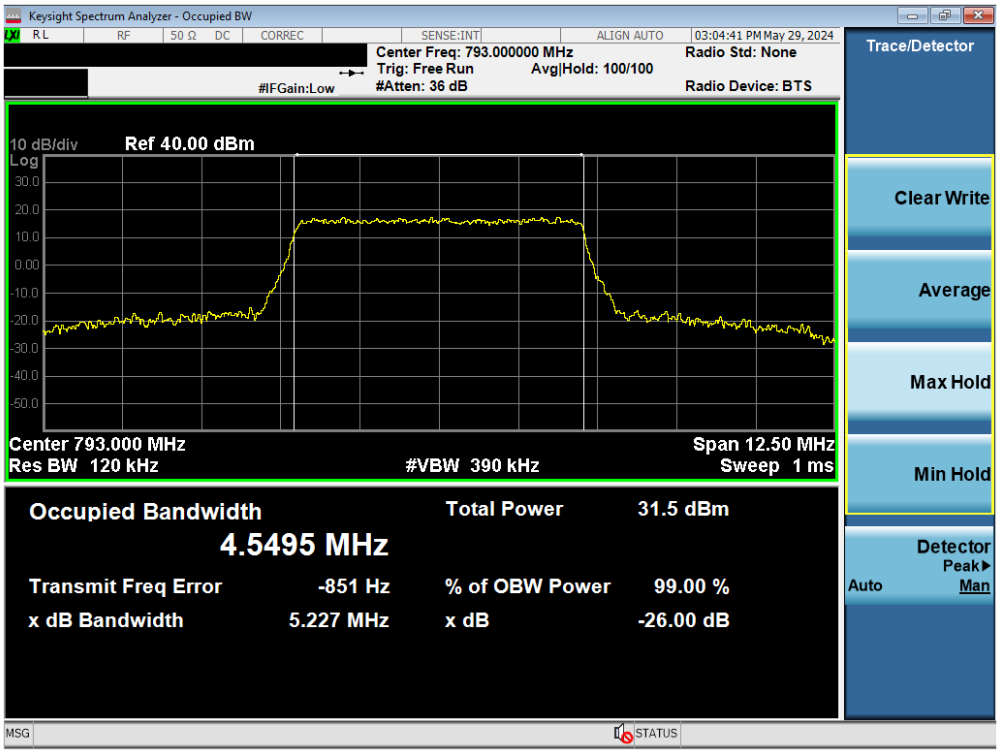


Plot 7-17. Occupied Bandwidth Plot (LTE Band 14 - 5MHz QPSK - Full RB)

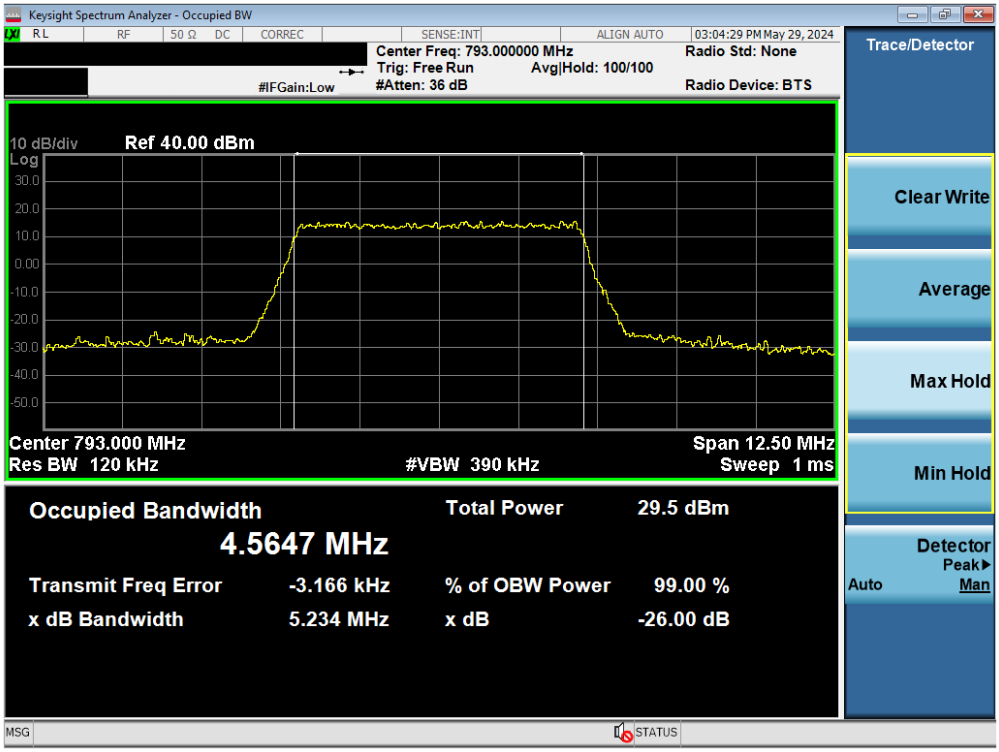


Plot 7-18. Occupied Bandwidth Plot (LTE Band 14 - 5MHz 16-QAM - Full RB)

Unless otherwise specified, no part of this report may be reproduced or utilized in any part, form or by any means, electronic or mechanical, including photocopying and microfilm, without permission in writing from Element Materials Technology. If you have any questions about this or have an enquiry about obtaining additional rights to this report or assembly of contents thereof, please contact ct.info@element.com.

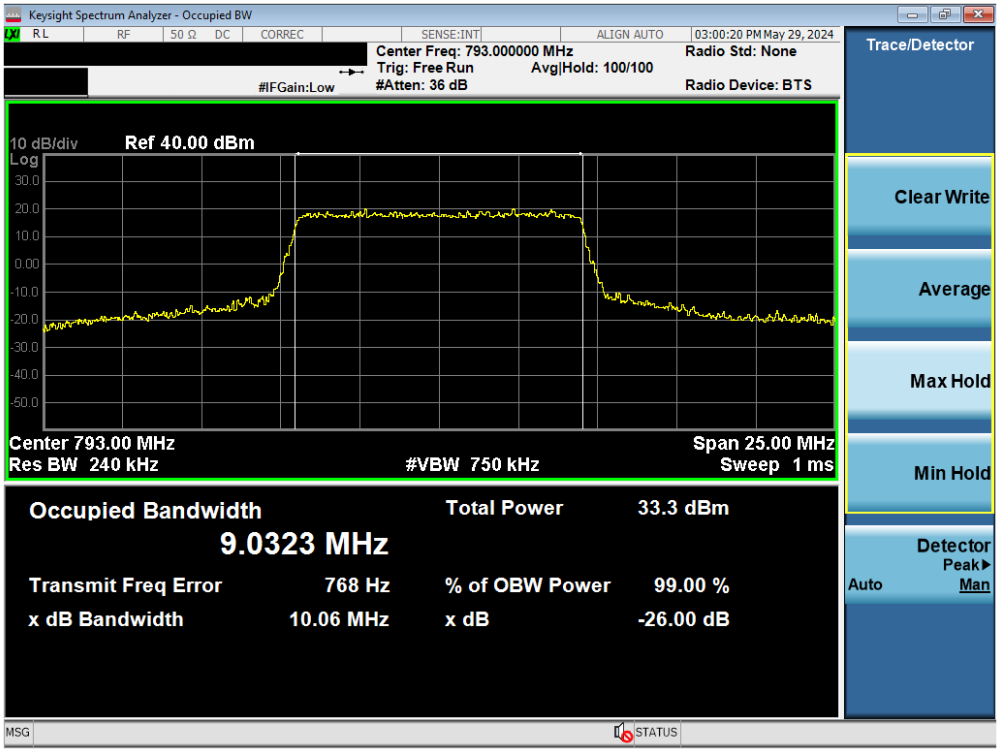


Plot 7-19. Occupied Bandwidth Plot (LTE Band 14 - 5MHz 64-QAM - Full RB)



Plot 7-20. Occupied Bandwidth Plot (LTE Band 14 - 5MHz 256-QAM - Full RB)

Unless otherwise specified, no part of this report may be reproduced or utilized in any part, form or by any means, electronic or mechanical, including photocopying and microfilm, without permission in writing from Element Materials Technology. If you have any questions about this or have an enquiry about obtaining additional rights to this report or assembly of contents thereof, please contact ct.info@element.com.

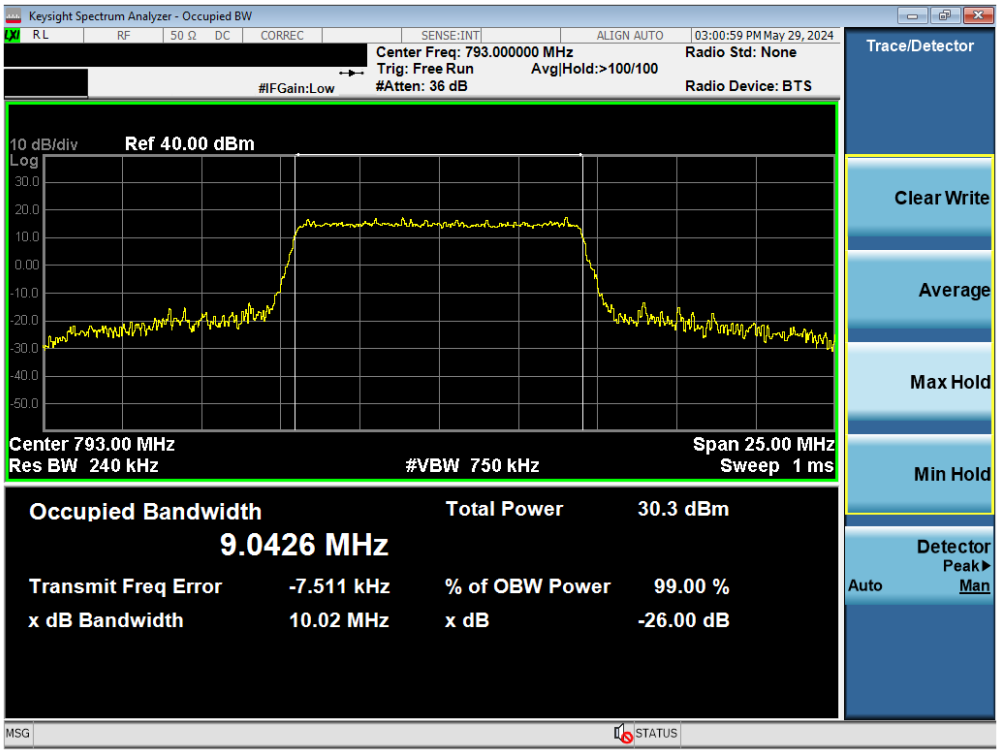


Plot 7-21. Occupied Bandwidth Plot (LTE Band 14 - 10MHz QPSK - Full RB)

Plot 7-22. Occupied Bandwidth Plot (LTE Band 14 - 10MHz 16-QAM - Full RB)

Unless otherwise specified, no part of this report may be reproduced or utilized in any part, form or by any means, electronic or mechanical, including photocopying and microfilm, without permission in writing from Element Materials Technology. If you have any questions about this or have an enquiry about obtaining additional rights to this report or assembly of contents thereof, please contact ct.info@element.com.

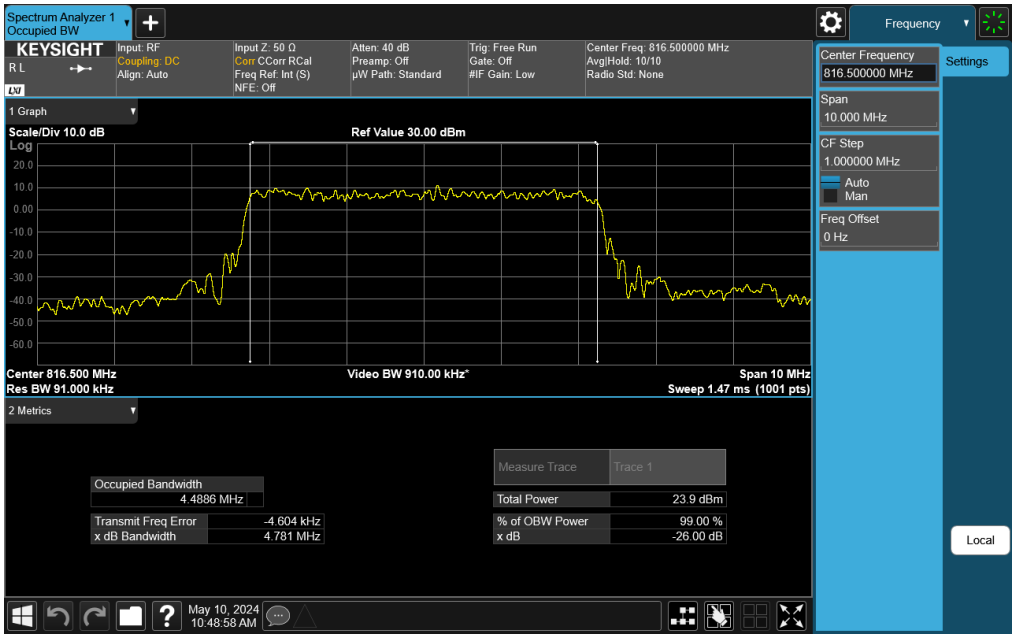
Plot 7-23. Occupied Bandwidth Plot (LTE Band 14 - 10MHz 64-QAM - Full RB)



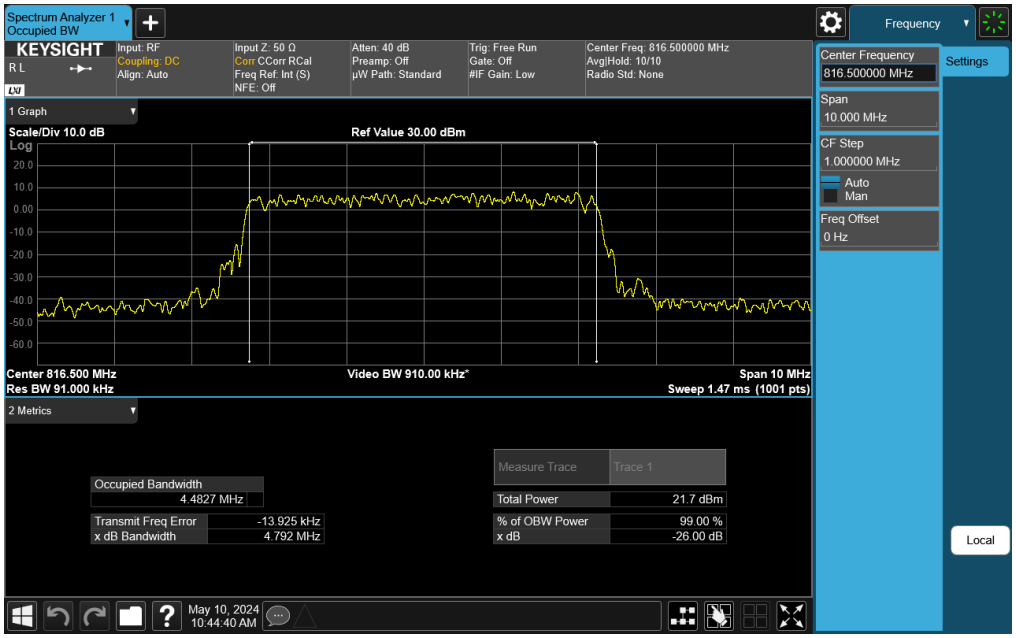
Plot 7-24. Occupied Bandwidth Plot (LTE Band 14 - 10MHz 256-QAM - Full RB)

Unless otherwise specified, no part of this report may be reproduced or utilized in any part, form or by any means, electronic or mechanical, including photocopying and microfilm, without permission in writing from Element Materials Technology. If you have any questions about this or have an enquiry about obtaining additional rights to this report or assembly of contents thereof, please contact ct.info@element.com.

NR Band n26



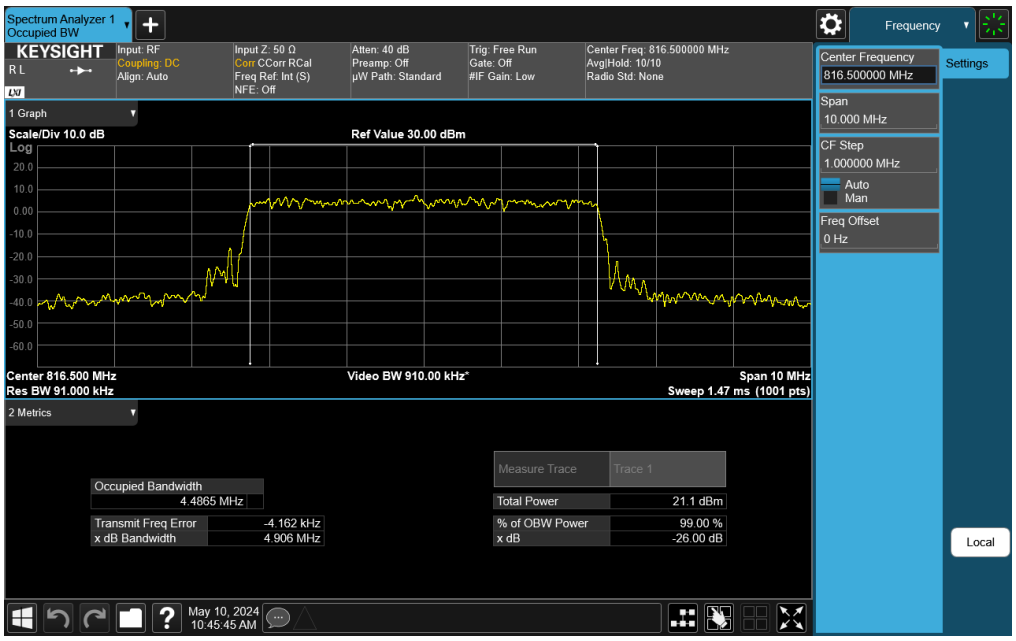
Plot 7-25. Occupied Bandwidth Plot (NR Band 26 - 5MHz DFT-s-OFDM π/2 BPSK - Full RB)



Plot 7-26. Occupied Bandwidth Plot (NR Band 26 - 5MHz CP-OFDM QPSK - Full RB)

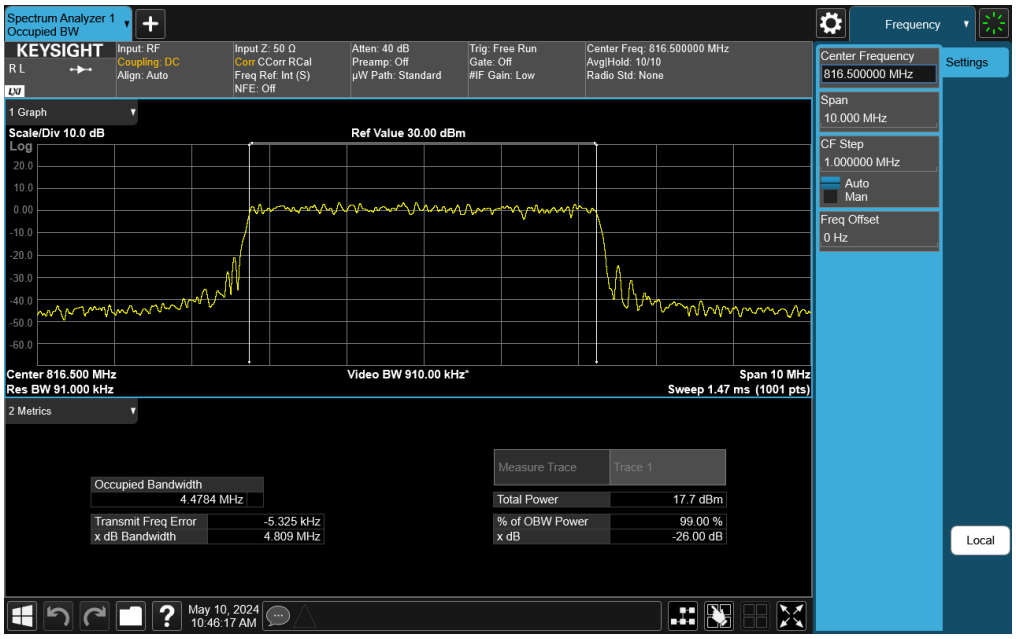
Unless otherwise specified, no part of this report may be reproduced or utilized in any part, form or by any means, electronic or mechanical, including photocopying and microfilm, without permission in writing from Element Materials Technology. If you have any questions about this or have an enquiry about obtaining additional rights to this report or assembly of contents thereof, please contact ct.info@element.com.

Plot 7-27. Occupied Bandwidth Plot (NR Band 26 - 5MHz CP-OFDM 16-QAM - Full RB)

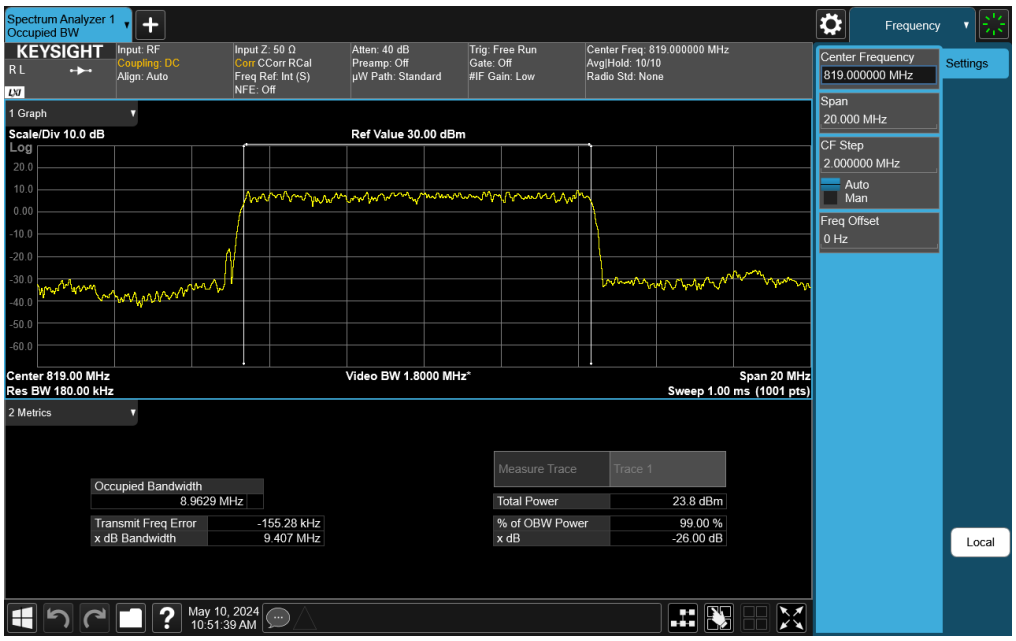


Plot 7-28. Occupied Bandwidth Plot (NR Band 26 - 5MHz CP-OFDM 64-QAM - Full RB)

Unless otherwise specified, no part of this report may be reproduced or utilized in any part, form or by any means, electronic or mechanical, including photocopying and microfilm, without permission in writing from Element Materials Technology. If you have any questions about this or have an enquiry about obtaining additional rights to this report or assembly of contents thereof, please contact ct.info@element.com.

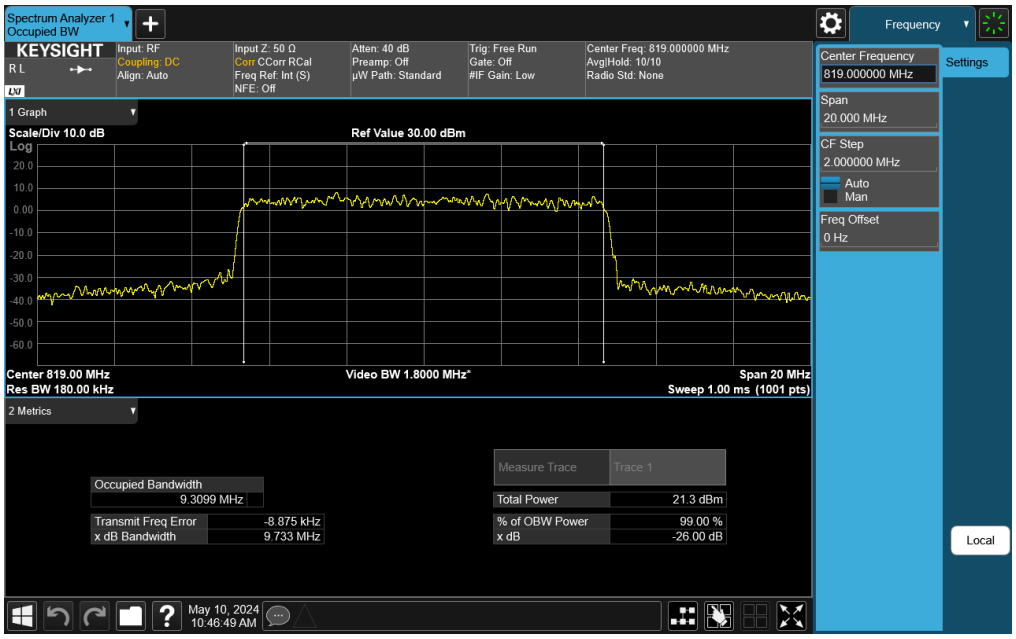


Plot 7-29. Occupied Bandwidth Plot (NR Band 26 - 5MHz CP-OFDM 256-QAM - Full RB)

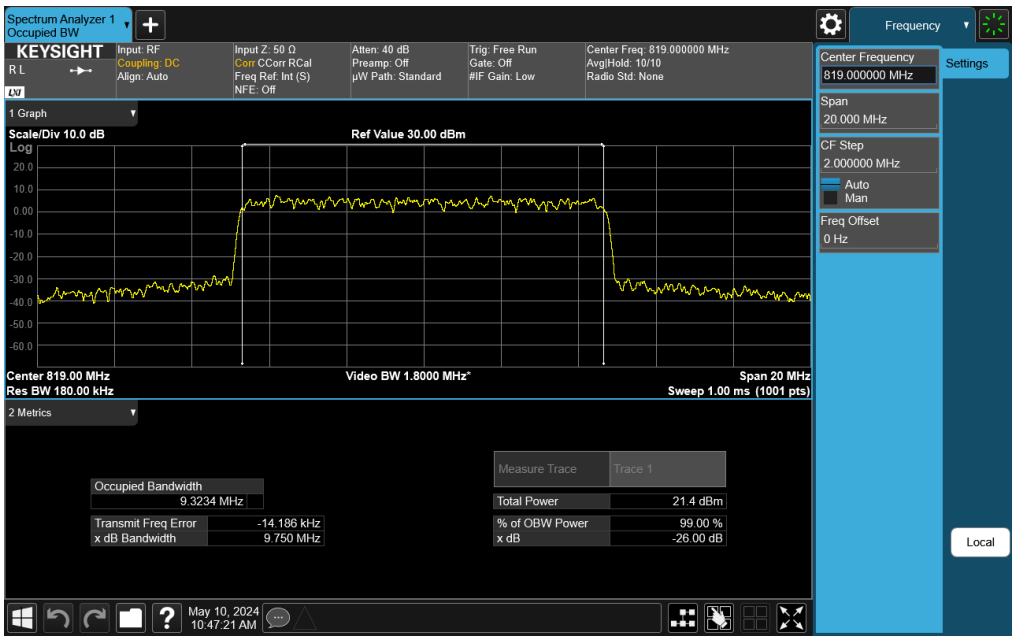


Plot 7-30. Occupied Bandwidth Plot (NR Band 26 - 10MHz DFT-s-OFDM π/2 BPSK - Full RB)

Unless otherwise specified, no part of this report may be reproduced or utilized in any part, form or by any means, electronic or mechanical, including photocopying and microfilm, without permission in writing from Element Materials Technology. If you have any questions about this or have an enquiry about obtaining additional rights to this report or assembly of contents thereof, please contact ct.info@element.com.

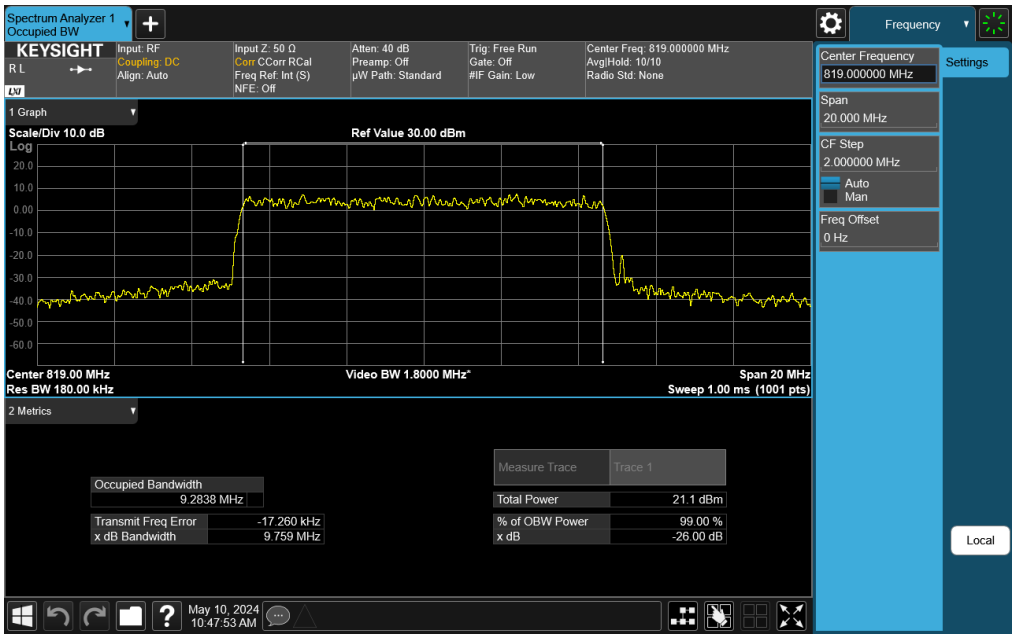


Plot 7-31. Occupied Bandwidth Plot (NR Band 26 - 10MHz CP-OFDM QPSK - Full RB)

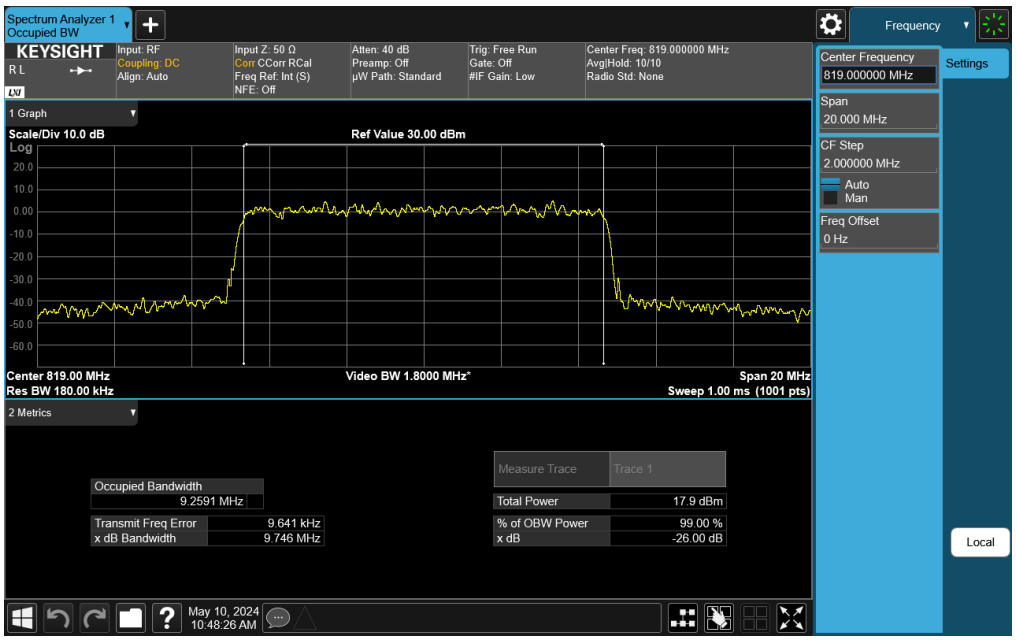


Plot 7-32. Occupied Bandwidth Plot (NR Band 26 - 10MHz CP-OFDM 16-QAM - Full RB)

Unless otherwise specified, no part of this report may be reproduced or utilized in any part, form or by any means, electronic or mechanical, including photocopying and microfilm, without permission in writing from Element Materials Technology. If you have any questions about this or have an enquiry about obtaining additional rights to this report or assembly of contents thereof, please contact ct.info@element.com.



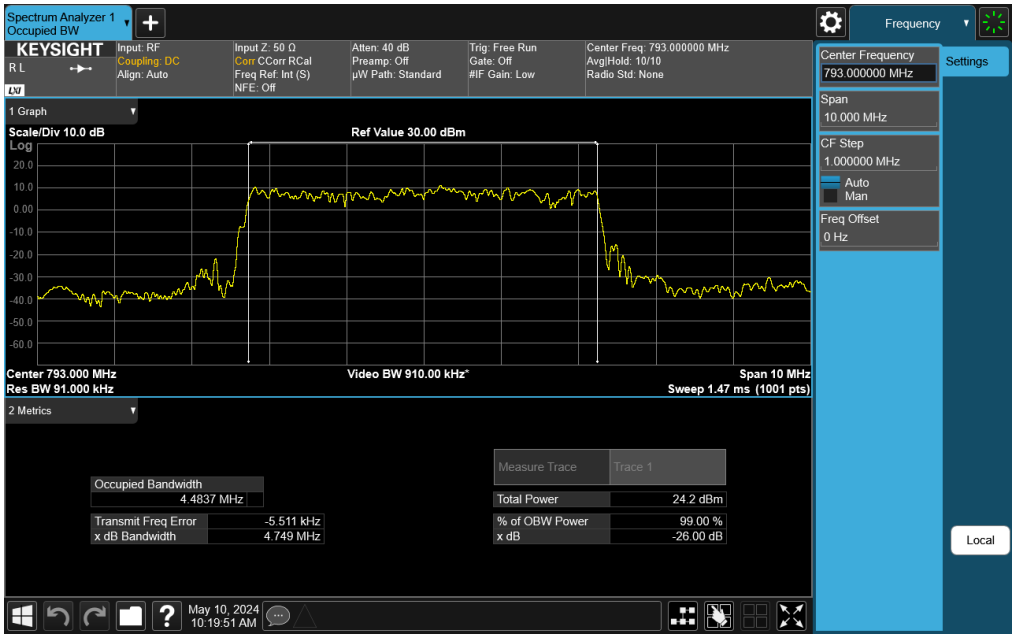
Plot 7-33. Occupied Bandwidth Plot (NR Band 26 - 10MHz CP-OFDM 64-QAM - Full RB)



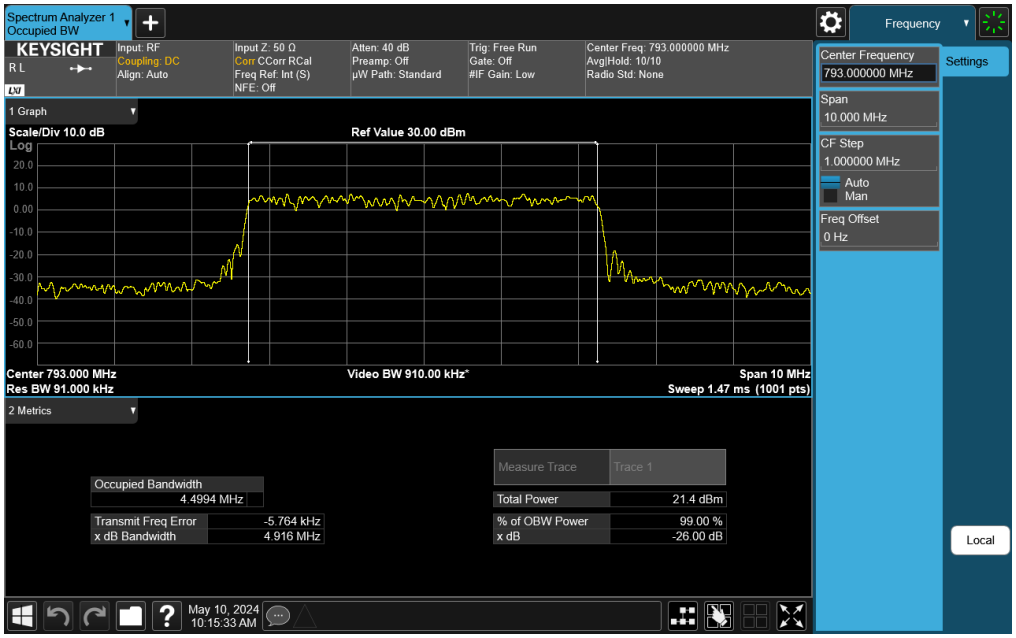
Plot 7-34. Occupied Bandwidth Plot (NR Band 26 - 10MHz CP-OFDM 256-QAM - Full RB)

Unless otherwise specified, no part of this report may be reproduced or utilized in any part, form or by any means, electronic or mechanical, including photocopying and microfilm, without permission in writing from Element Materials Technology. If you have any questions about this or have an enquiry about obtaining additional rights to this report or assembly of contents thereof, please contact ct.info@element.com.

NR Band n14

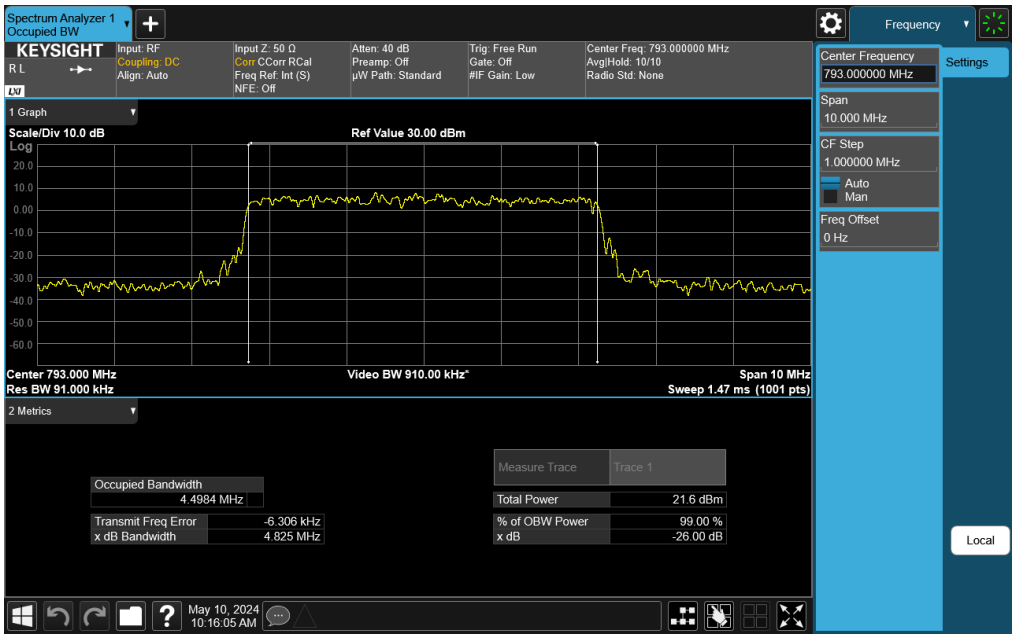


Plot 7-35. Occupied Bandwidth Plot (NR Band 14 - 5MHz DFT-s-OFDM π/2 BPSK - Full RB)



Plot 7-36. Occupied Bandwidth Plot (NR Band 14 - 5MHz CP-OFDM QPSK - Full RB)

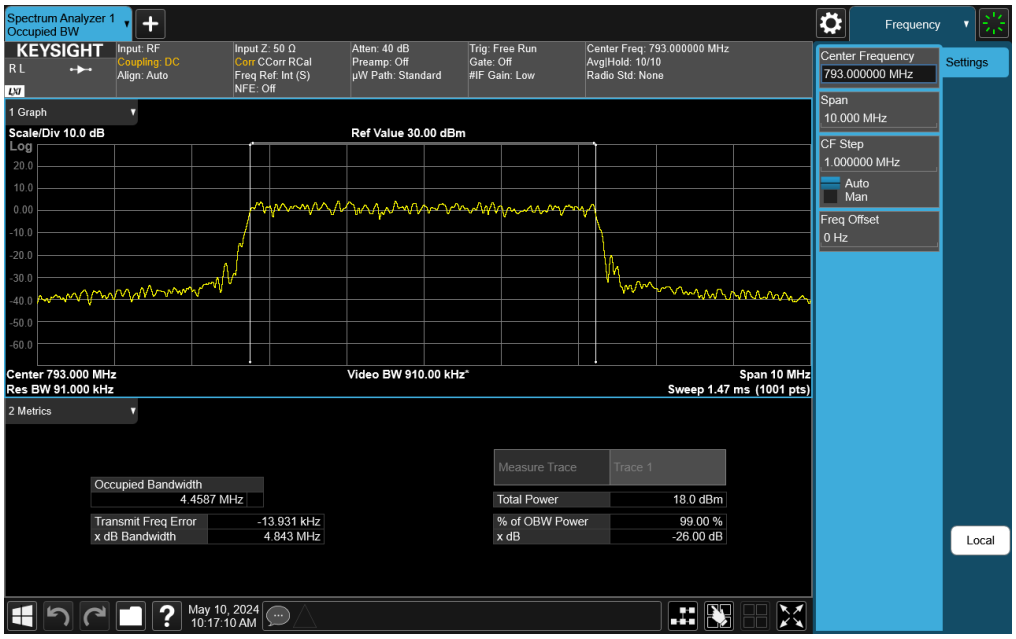
Unless otherwise specified, no part of this report may be reproduced or utilized in any part, form or by any means, electronic or mechanical, including photocopying and microfilm, without permission in writing from Element Materials Technology. If you have any questions about this or have an enquiry about obtaining additional rights to this report or assembly of contents thereof, please contact ct.info@element.com.



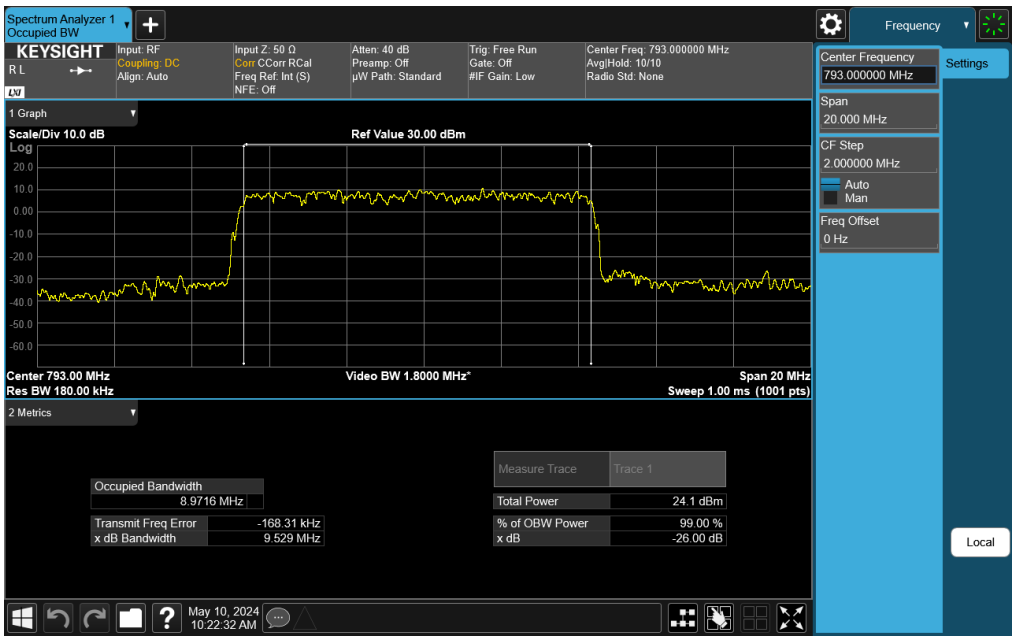
Plot 7-37. Occupied Bandwidth Plot (NR Band 14 - 5MHz CP-OFDM 16-QAM - Full RB)

Plot 7-38. Occupied Bandwidth Plot (NR Band 14 - 5MHz CP-OFDM 64-QAM - Full RB)

Unless otherwise specified, no part of this report may be reproduced or utilized in any part, form or by any means, electronic or mechanical, including photocopying and microfilm, without permission in writing from Element Materials Technology. If you have any questions about this or have an enquiry about obtaining additional rights to this report or assembly of contents thereof, please contact ct.info@element.com.

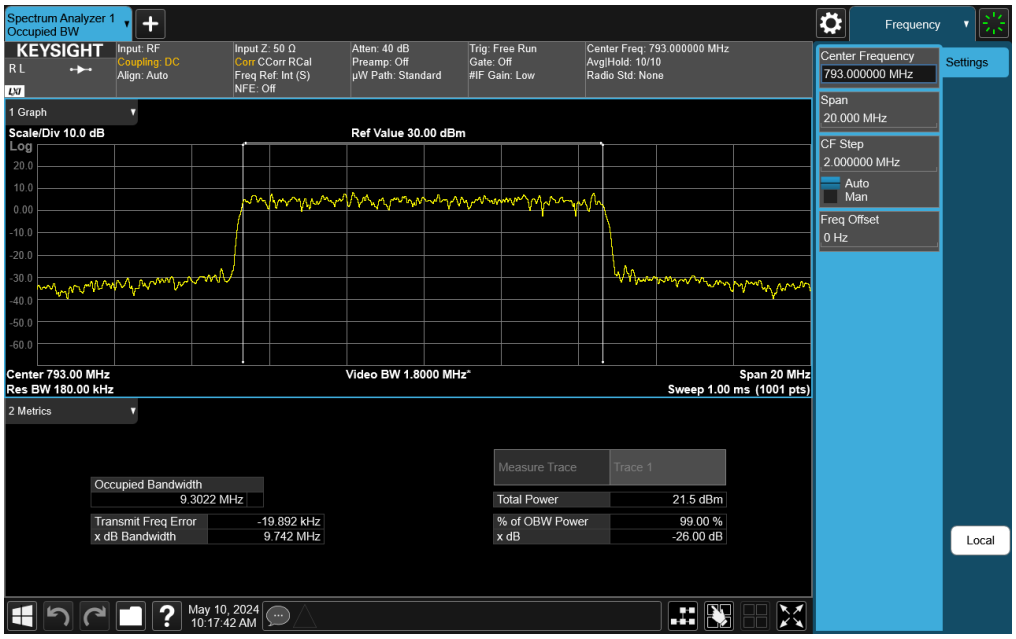


Plot 7-39. Occupied Bandwidth Plot (NR Band 14 - 5MHz CP-OFDM 256-QAM - Full RB)

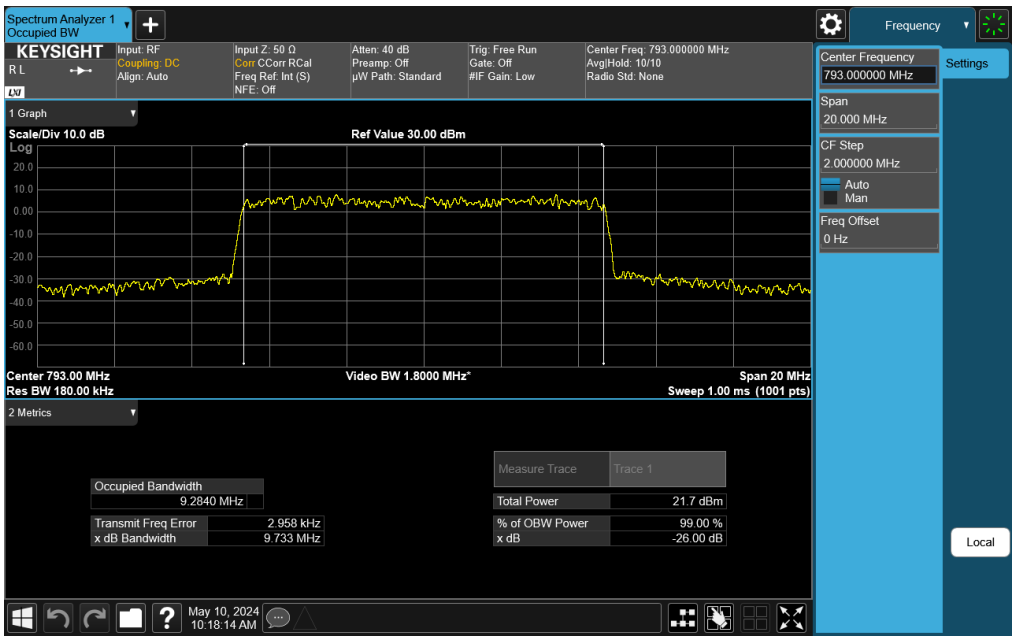


Plot 7-40. Occupied Bandwidth Plot (NR Band 14 - 10MHz DFT-s-OFDM π/2 BPSK - Full RB)

Unless otherwise specified, no part of this report may be reproduced or utilized in any part, form or by any means, electronic or mechanical, including photocopying and microfilm, without permission in writing from Element Materials Technology. If you have any questions about this or have an enquiry about obtaining additional rights to this report or assembly of contents thereof, please contact ct.info@element.com.

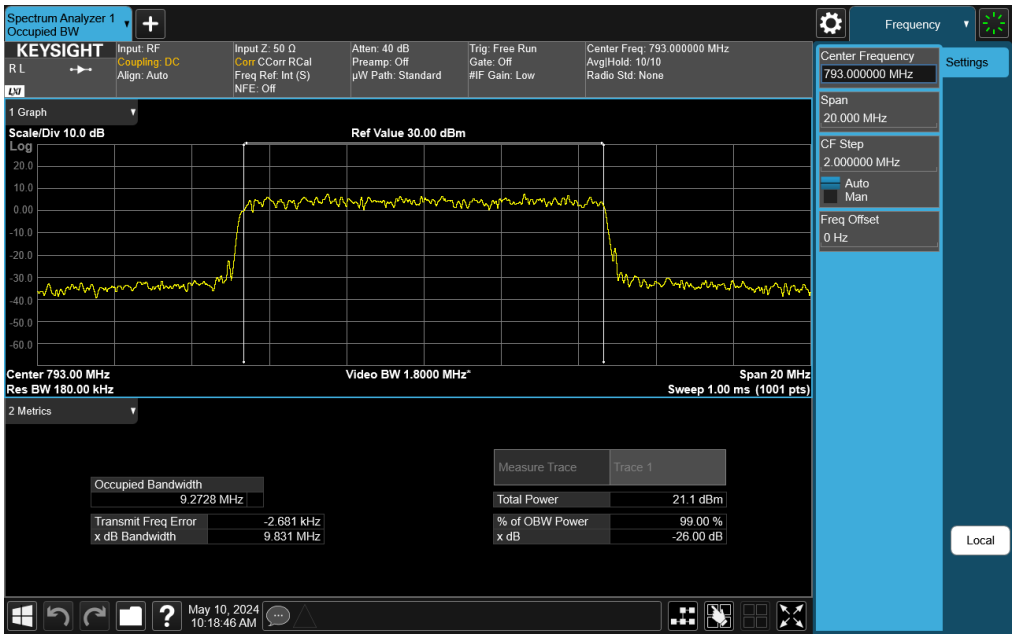


Plot 7-41. Occupied Bandwidth Plot (NR Band 14 - 10MHz CP-OFDM QPSK - Full RB)

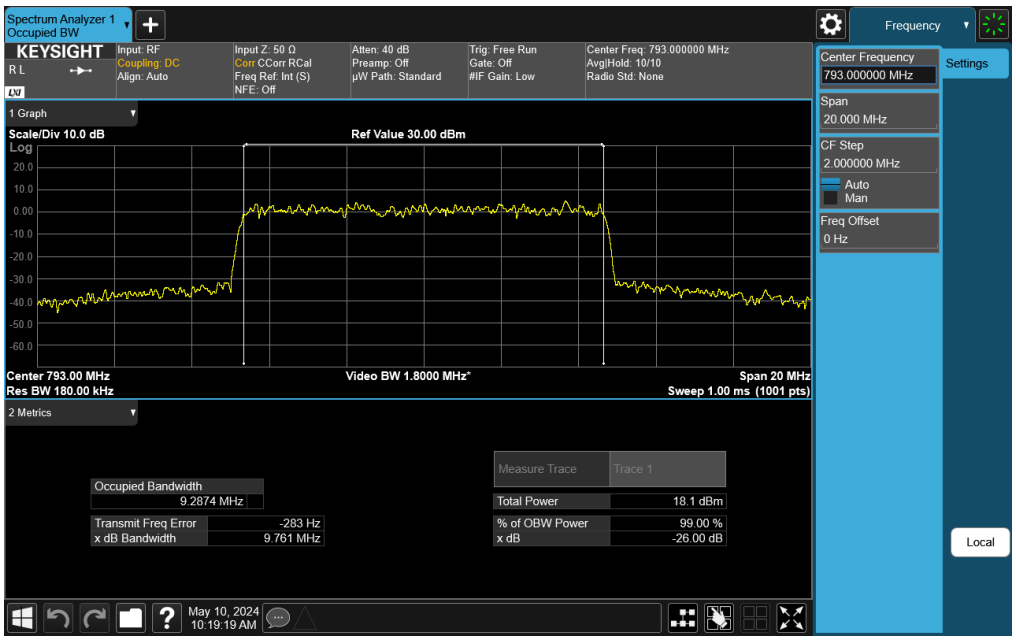


Plot 7-42. Occupied Bandwidth Plot (NR Band 14 - 10MHz CP-OFDM 16-QAM - Full RB)

Unless otherwise specified, no part of this report may be reproduced or utilized in any part, form or by any means, electronic or mechanical, including photocopying and microfilm, without permission in writing from Element Materials Technology. If you have any questions about this or have an enquiry about obtaining additional rights to this report or assembly of contents thereof, please contact ct.info@element.com.



Plot 7-43. Occupied Bandwidth Plot (NR Band 14 - 10MHz CP-OFDM 64-QAM - Full RB)



Plot 7-44. Occupied Bandwidth Plot (NR Band 14 - 10MHz CP-OFDM 256-QAM - Full RB)

Unless otherwise specified, no part of this report may be reproduced or utilized in any part, form or by any means, electronic or mechanical, including photocopying and microfilm, without permission in writing from Element Materials Technology. If you have any questions about this or have an enquiry about obtaining additional rights to this report or assembly of contents thereof, please contact ct.info@element.com.

7.3 Spurious and Harmonic Emissions at Antenna Terminal

§2.1051 §90.691(a) §90.543(e)

Test Overview

The level of the carrier and the various conducted spurious and harmonic frequencies is measured by means of a calibrated spectrum analyzer. The spectrum is scanned from the lowest frequency generated in the equipment up to a frequency including its 10th harmonic. All out of band emissions are measured with a spectrum analyzer connected to the antenna terminal of the EUT while the EUT is operating at maximum power, and at the appropriate frequencies. All data rates were investigated to determine the worst case configuration. All modes of operation and all ports were investigated and the worst case configuration results are reported in this section.

The minimum permissible attenuation level of any spurious emission is $43 + 10 \log_{10}(P_{[Watts]})$, where P is the transmitter power in Watts.

Test Procedure Used

KDB 971168 D01 v03r01 – Section 6.0

Test Settings

1. Start frequency was set to 30MHz and stop frequency was set to 10GHz (separated into at least two plots per channel)
2. RBW ≥ 100kHz
3. VBW ≥ 3 x RBW
4. Detector = RMS
5. Trace mode = max hold
6. Sweep time = auto couple
7. The trace was allowed to stabilize

Unless otherwise specified, no part of this report may be reproduced or utilized in any part, form or by any means, electronic or mechanical, including photocopying and microfilm, without permission in writing from Element Materials Technology. If you have any questions about this or have an enquiry about obtaining additional rights to this report or assembly of contents thereof, please contact ct.info@element.com.

Test Setup

The EUT and measurement equipment were set up as shown in the diagram below.

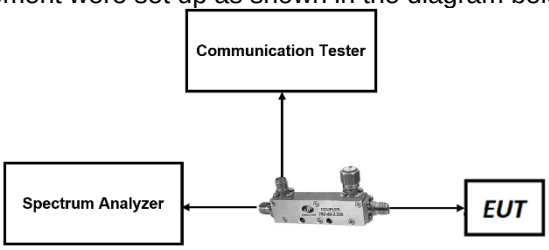


Figure 7-3. LTE Test Instrument & Measurement Setup

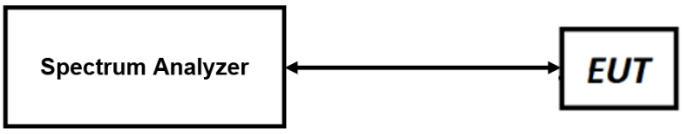


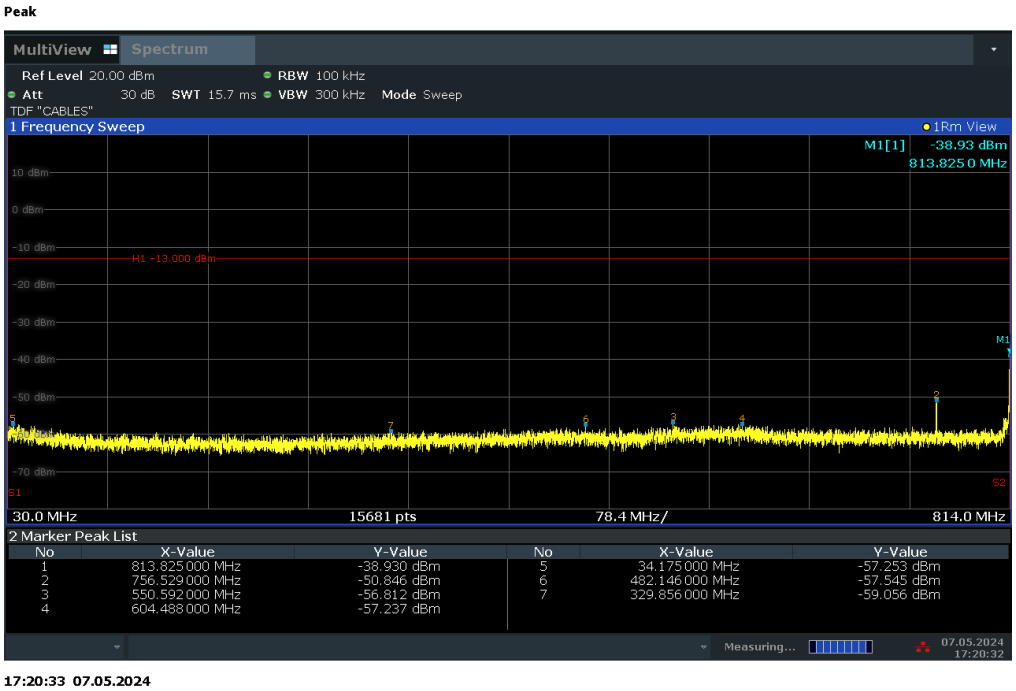
Figure 7-4. FR1 Test Instrument & Measurement Setup

Test Notes

Compliance with the applicable limits is based on the use of measurement instrumentation employing a resolution bandwidth of 100 kHz or greater for Part 90. However, in the 1 MHz bands immediately outside and adjacent to the frequency block a resolution bandwidth of at least one percent of the emission bandwidth of the fundamental emission of the transmitter may be employed. The emission bandwidth is defined as the width of the signal between two points, one below the carrier center frequency and one above the carrier center frequency, outside of which all emission are attenuated at least 26 dB below the transmitter power.

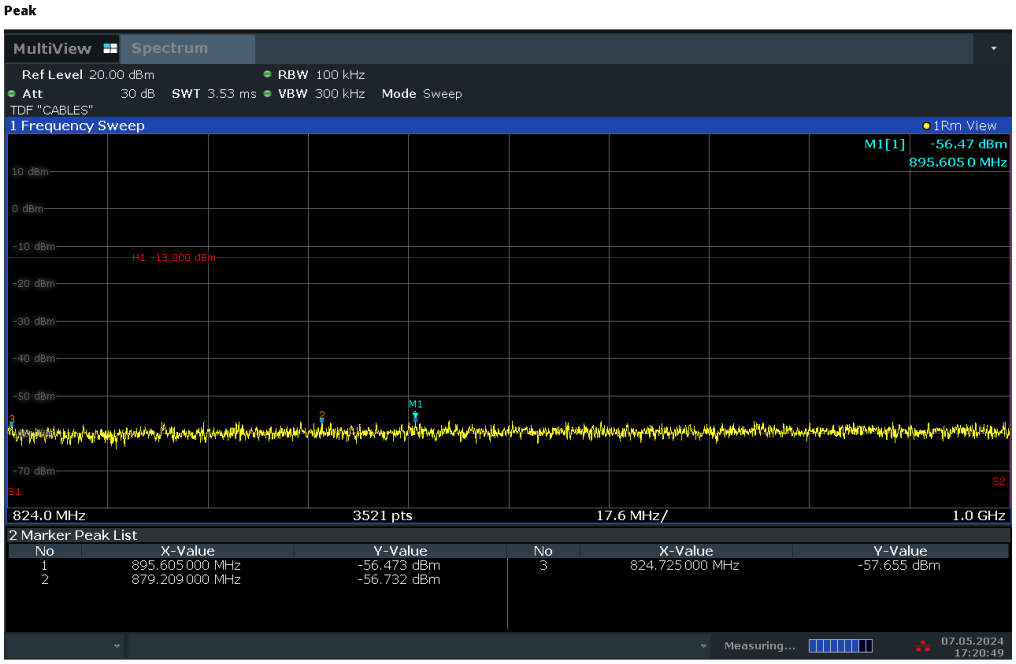
Unless otherwise specified, no part of this report may be reproduced or utilized in any part, form or by any means, electronic or mechanical, including photocopying and microfilm, without permission in writing from Element Materials Technology. If you have any questions about this or have an enquiry about obtaining additional rights to this report or assembly of contents thereof, please contact ct.info@element.com.

LTE Band 26



17:20:33 07.05.2024

Plot 7-45. Conducted Spurious Plot (LTE Band 26 - 5MHz QPSK - RB Size 1, RB Offset 0 - Low Channel)

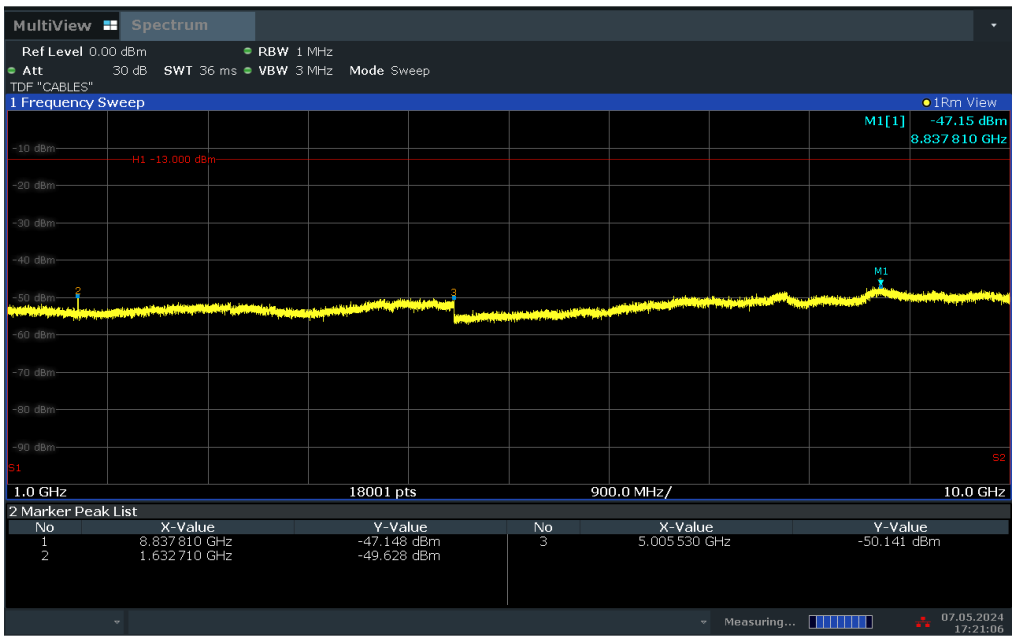


17:20:49 07.05.2024

Plot 7-46. Conducted Spurious Plot (LTE Band 26 - 5MHz QPSK - RB Size 1, RB Offset 0 - Low Channel)

Unless otherwise specified, no part of this report may be reproduced or utilized in any part, form or by any means, electronic or mechanical, including photocopying and microfilm, without permission in writing from Element Materials Technology. If you have any questions about this or have an enquiry about obtaining additional rights to this report or assembly of contents thereof, please contact ct.info@element.com.

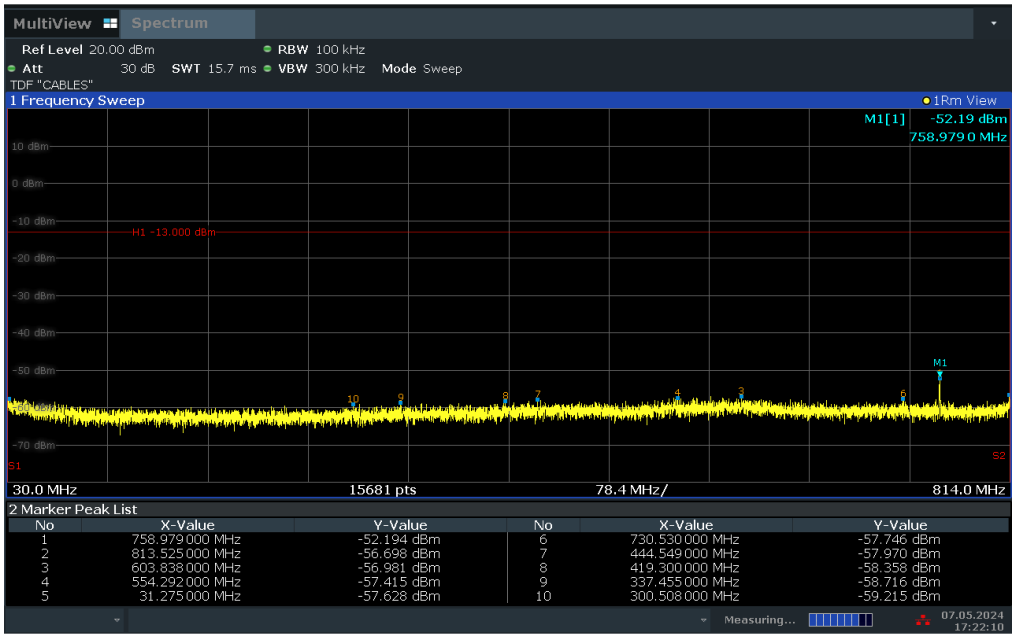
Peak



17:21:06 07.05.2024

Plot 7-47. Conducted Spurious Plot (LTE Band 26 - 5MHz QPSK - RB Size 1, RB Offset 0 - Low Channel)

Peak

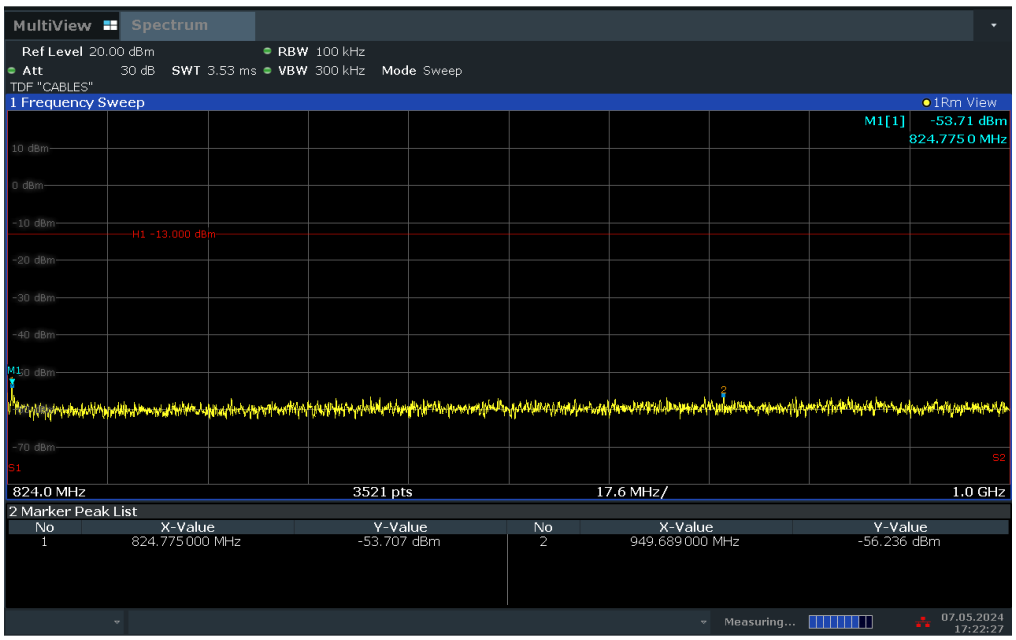


17:22:10 07.05.2024

Plot 7-48. Conducted Spurious Plot (LTE Band 26 - 10MHz QPSK - RB Size 1, RB Offset 0 - Mid Channel)

Unless otherwise specified, no part of this report may be reproduced or utilized in any part, form or by any means, electronic or mechanical, including photocopying and microfilm, without permission in writing from Element Materials Technology. If you have any questions about this or have an enquiry about obtaining additional rights to this report or assembly of contents thereof, please contact ct.info@element.com.

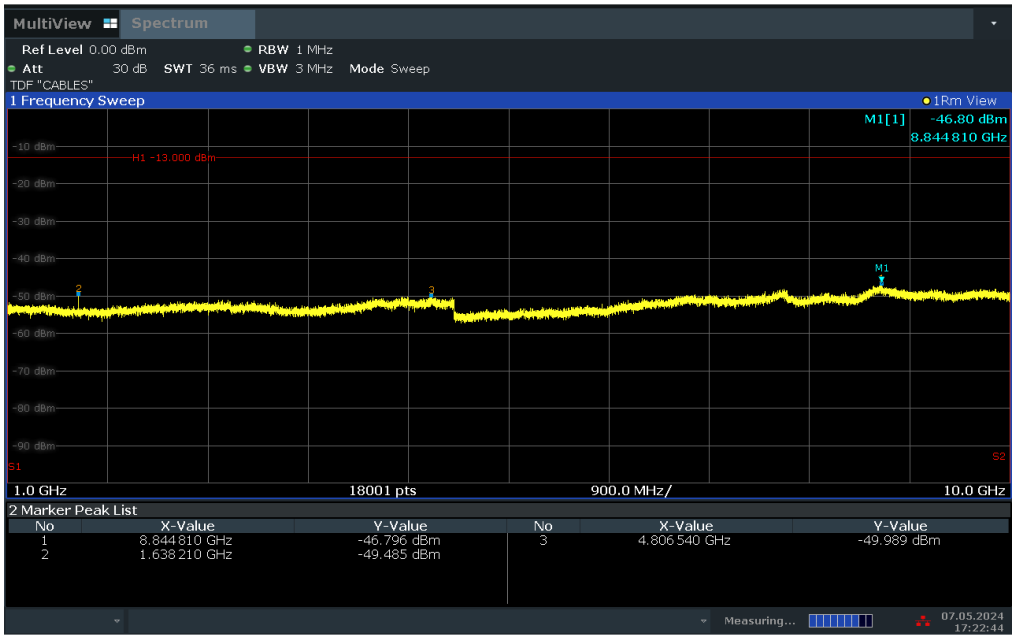
Peak



17:22:27 07.05.2024

Plot 7-49. Conducted Spurious Plot (LTE Band 26 - 10MHz QPSK - RB Size 1, RB Offset 0 - Mid Channel)

Peak

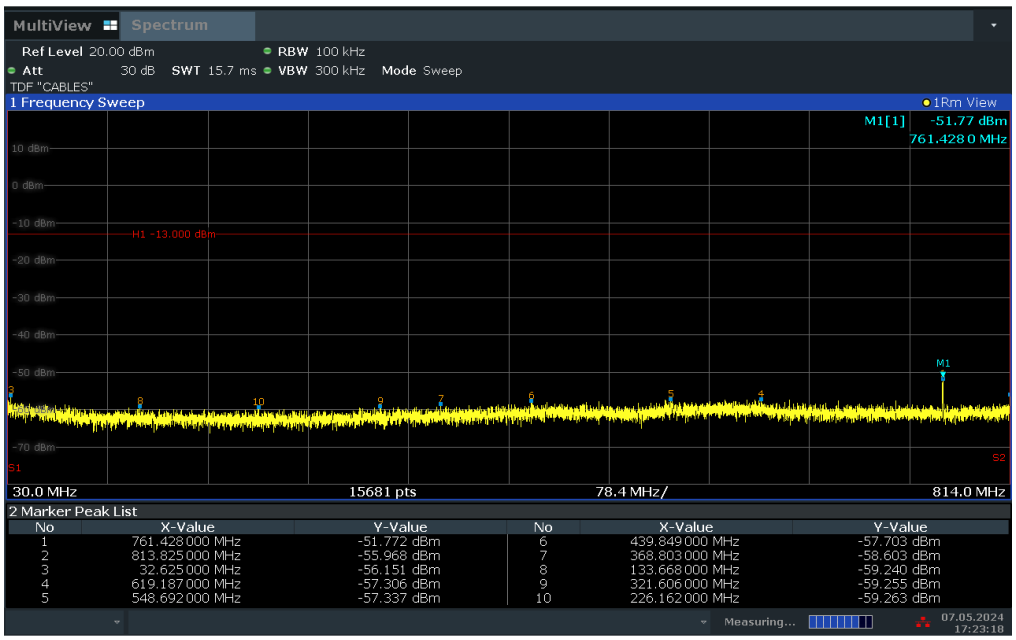


17:22:44 07.05.2024

Plot 7-50. Conducted Spurious Plot (LTE Band 26 - 10MHz QPSK - RB Size 1, RB Offset 0 - Mid Channel)

Unless otherwise specified, no part of this report may be reproduced or utilized in any part, form or by any means, electronic or mechanical, including photocopying and microfilm, without permission in writing from Element Materials Technology. If you have any questions about this or have an enquiry about obtaining additional rights to this report or assembly of contents thereof, please contact ct.info@element.com.

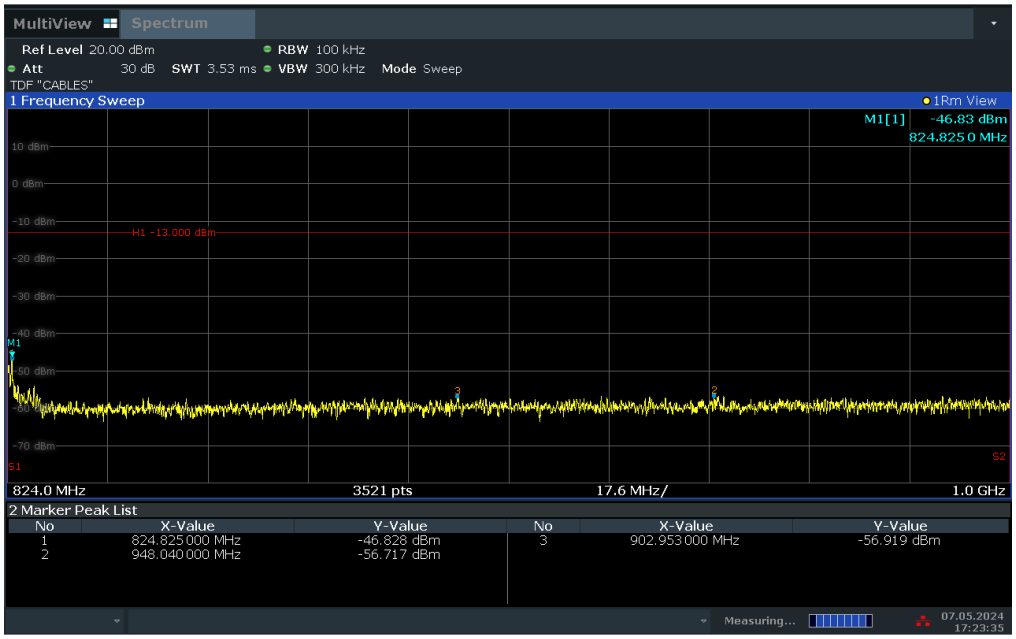
Peak



17:23:18 07.05.2024

Plot 7-51. Conducted Spurious Plot (LTE Band 26 - 5MHz QPSK - RB Size 1, RB Offset 0 - High Channel)

Peak

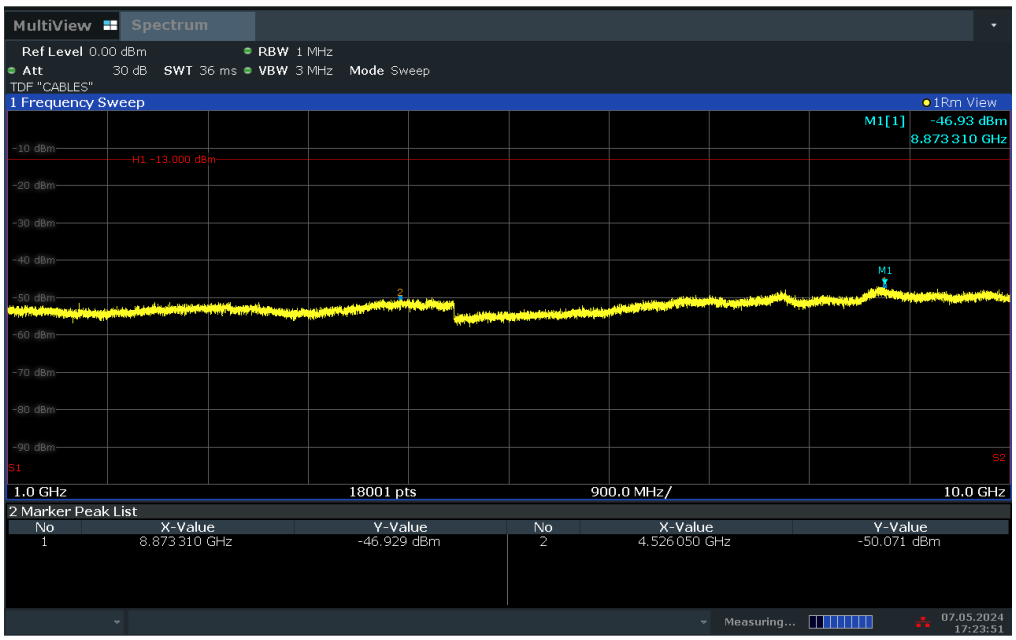


17:23:35 07.05.2024

Plot 7-52. Conducted Spurious Plot (LTE Band 26 - 5MHz QPSK - RB Size 1, RB Offset 0 - High Channel)

Unless otherwise specified, no part of this report may be reproduced or utilized in any part, form or by any means, electronic or mechanical, including photocopying and microfilm, without permission in writing from Element Materials Technology. If you have any questions about this or have an enquiry about obtaining additional rights to this report or assembly of contents thereof, please contact ct.info@element.com.

Peak



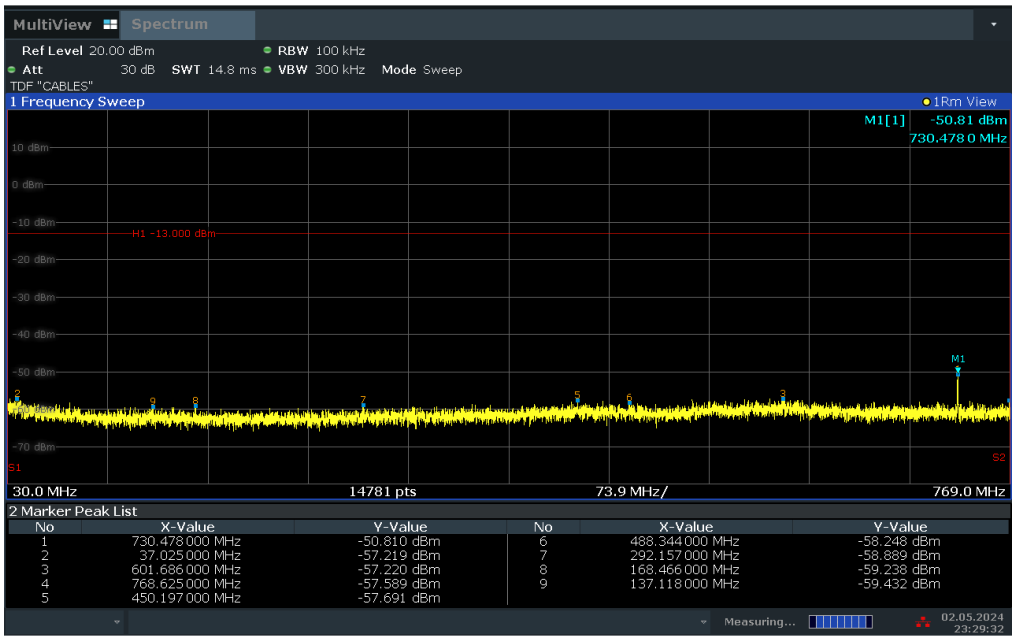
17:23:52 07.05.2024

Plot 7-53. Conducted Spurious Plot (LTE Band 26 - 5MHz QPSK - RB Size 1, RB Offset 0 - High Channel)

Unless otherwise specified, no part of this report may be reproduced or utilized in any part, form or by any means, electronic or mechanical, including photocopying and microfilm, without permission in writing from Element Materials Technology. If you have any questions about this or have an enquiry about obtaining additional rights to this report or assembly of contents thereof, please contact ct.info@element.com.

LTE Band 14

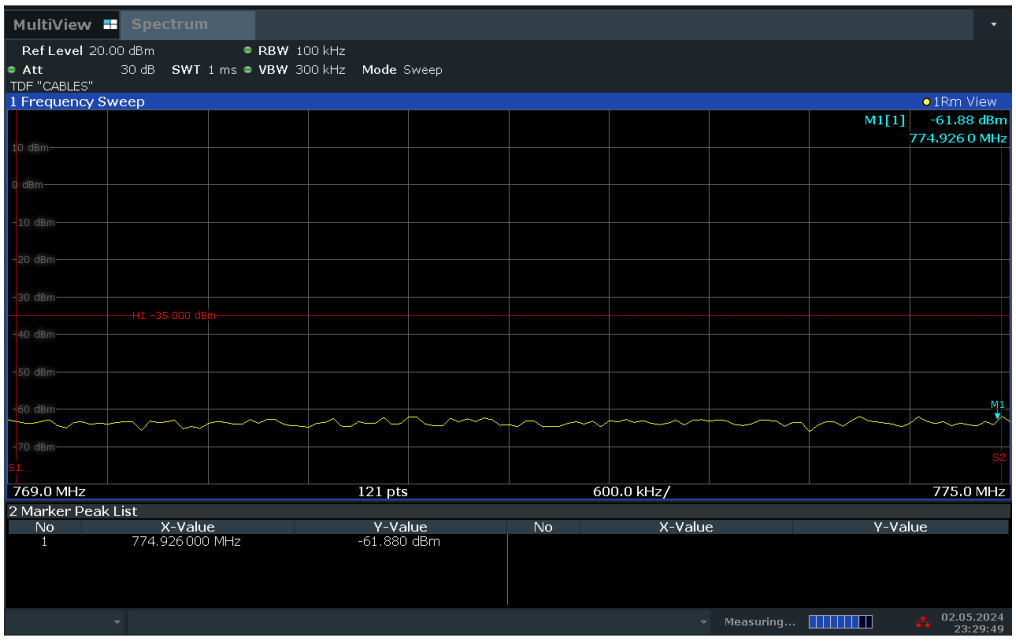
Peak



23:29:32 02.05.2024

Plot 7-54. Conducted Spurious Plot (LTE Band 14 - 5MHz QPSK - RB Size 1, RB Offset 0 - Low Channel)

Peak

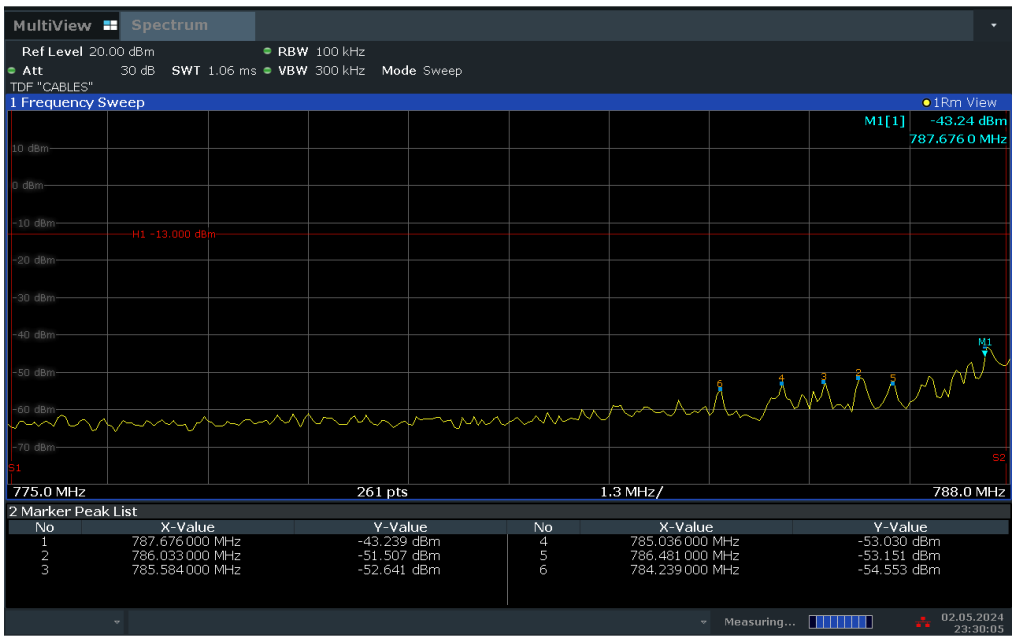


23:29:49 02.05.2024

Plot 7-55. Conducted Spurious Plot (LTE Band 14 - 5MHz QPSK - RB Size 1, RB Offset 0 - Low Channel)

Unless otherwise specified, no part of this report may be reproduced or utilized in any part, form or by any means, electronic or mechanical, including photocopying and microfilm, without permission in writing from Element Materials Technology. If you have any questions about this or have an enquiry about obtaining additional rights to this report or assembly of contents thereof, please contact ct.info@element.com.

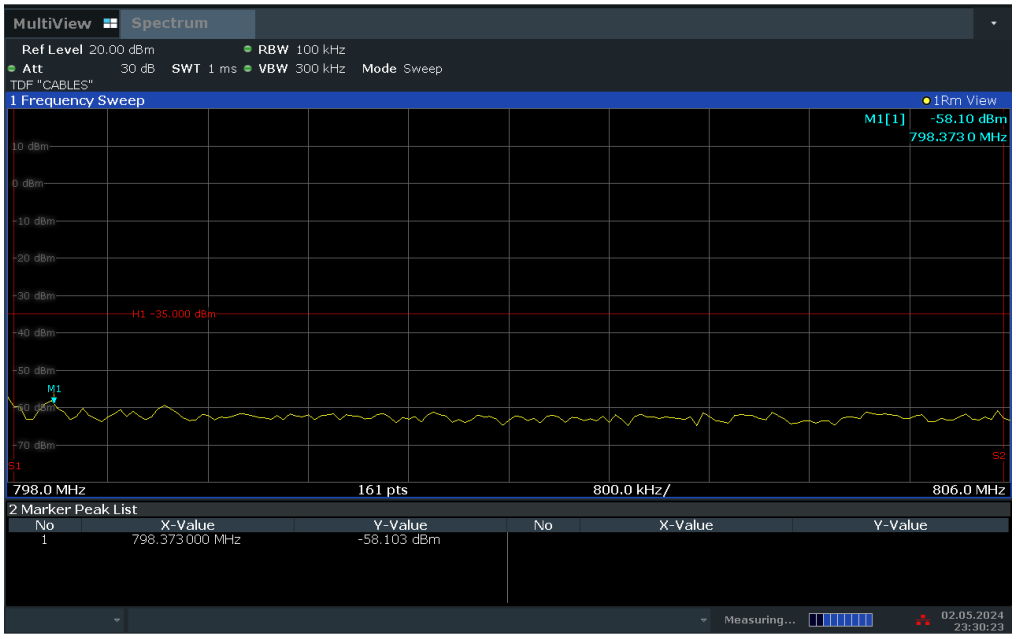
Peak



23:30:06 02.05.2024

Plot 7-56. Conducted Spurious Plot (LTE Band 14 - 5MHz QPSK - RB Size 1, RB Offset 0 - Low Channel)

Peak

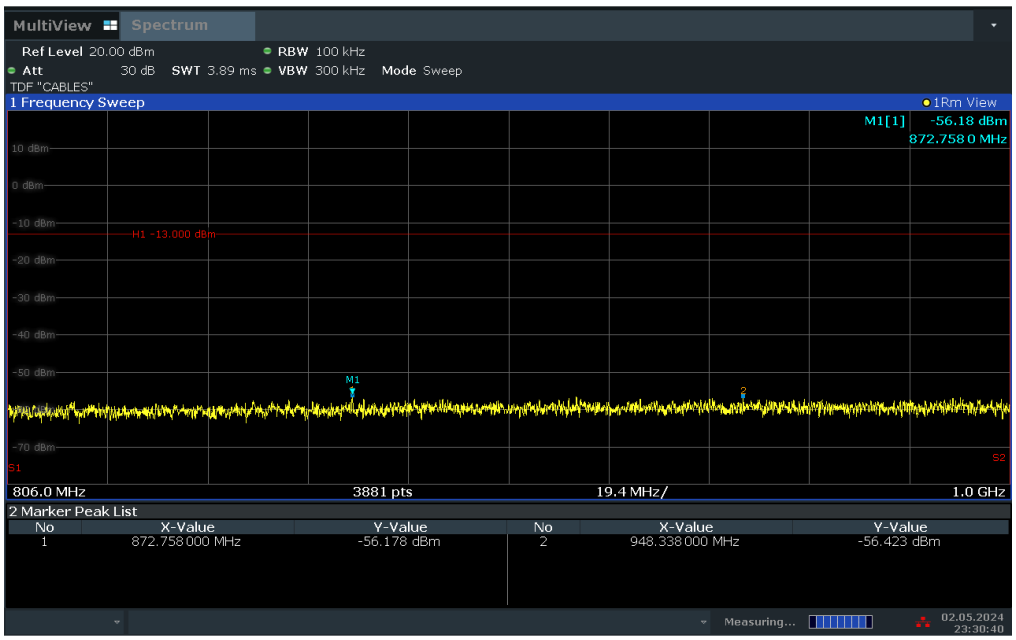


23:30:23 02.05.2024

Plot 7-57. Conducted Spurious Plot (LTE Band 14 - 5MHz QPSK - RB Size 1, RB Offset 0 - Low Channel)

Unless otherwise specified, no part of this report may be reproduced or utilized in any part, form or by any means, electronic or mechanical, including photocopying and microfilm, without permission in writing from Element Materials Technology. If you have any questions about this or have an enquiry about obtaining additional rights to this report or assembly of contents thereof, please contact ct.info@element.com.

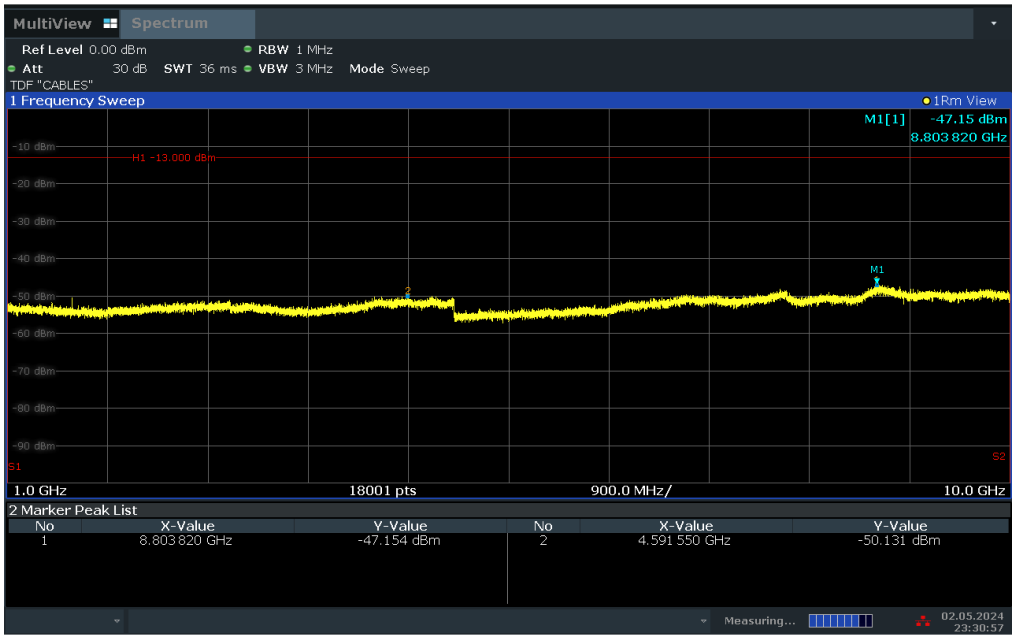
Peak



23:30:41 02.05.2024

Plot 7-58. Conducted Spurious Plot (LTE Band 14 - 5MHz QPSK - RB Size 1, RB Offset 0 - Low Channel)

Peak

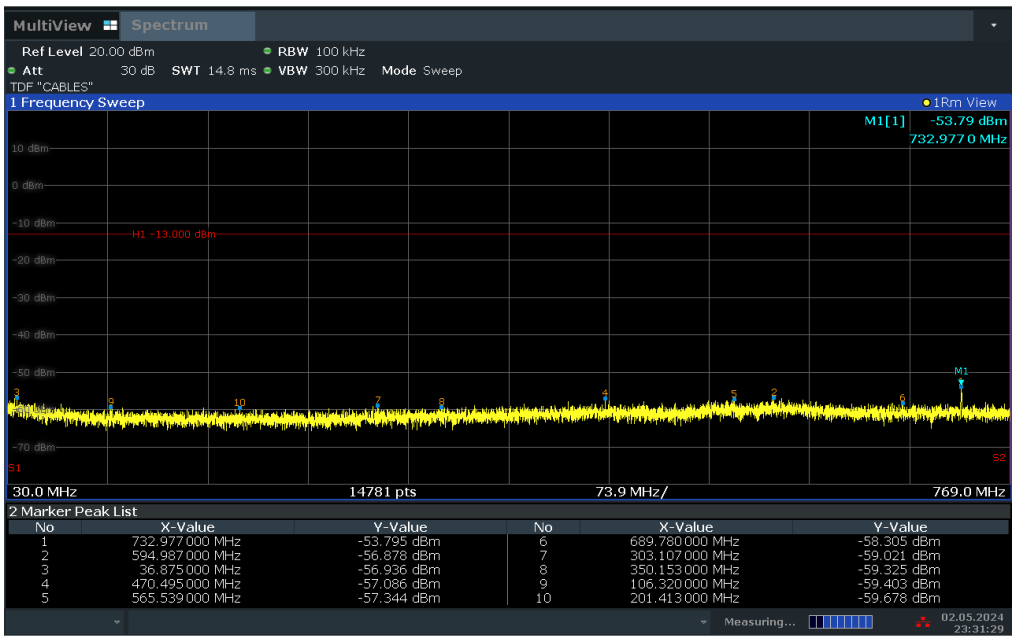


23:30:58 02.05.2024

Plot 7-59. Conducted Spurious Plot (LTE Band 14 - 5MHz QPSK - RB Size 1, RB Offset 0 - Low Channel)

Unless otherwise specified, no part of this report may be reproduced or utilized in any part, form or by any means, electronic or mechanical, including photocopying and microfilm, without permission in writing from Element Materials Technology. If you have any questions about this or have an enquiry about obtaining additional rights to this report or assembly of contents thereof, please contact ct.info@element.com.

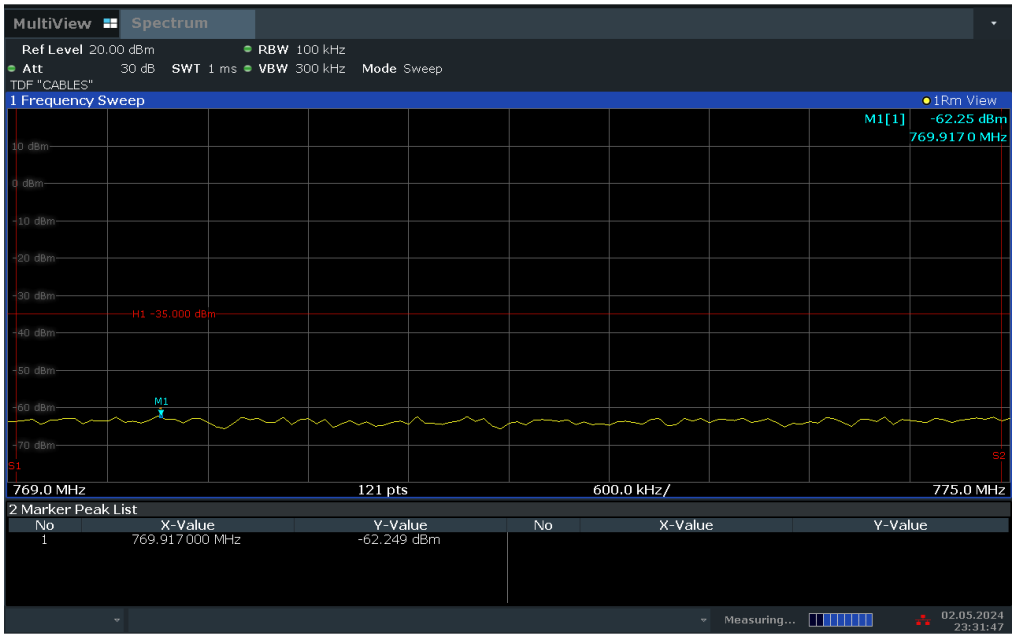
Peak



23:31:30 02.05.2024

Plot 7-60. Conducted Spurious Plot (LTE Band 14 - 10MHz QPSK - RB Size 1, RB Offset 0 - Mid Channel)

Peak

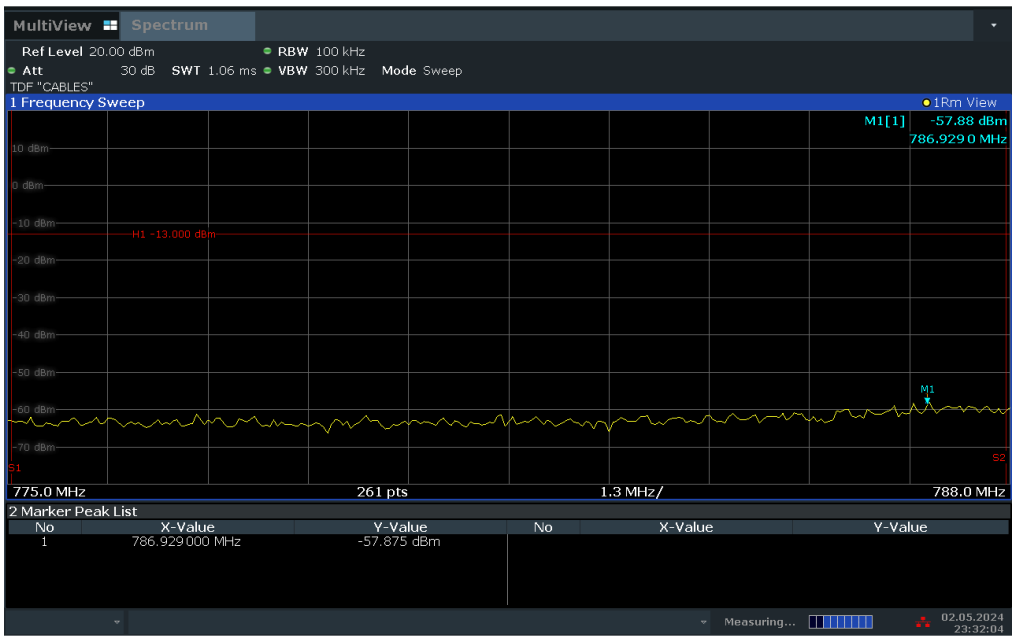


23:31:47 02.05.2024

Plot 7-61. Conducted Spurious Plot (LTE Band 14 - 10MHz QPSK - RB Size 1, RB Offset 0 - Mid Channel)

Unless otherwise specified, no part of this report may be reproduced or utilized in any part, form or by any means, electronic or mechanical, including photocopying and microfilm, without permission in writing from Element Materials Technology. If you have any questions about this or have an enquiry about obtaining additional rights to this report or assembly of contents thereof, please contact ct.info@element.com.

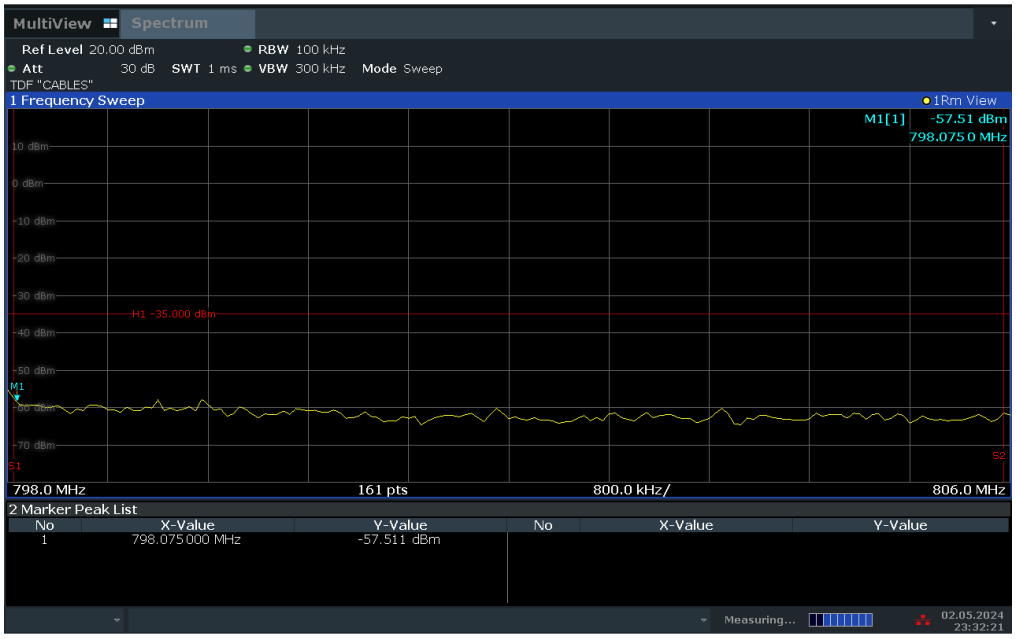
Peak



23:32:04 02.05.2024

Plot 7-62. Conducted Spurious Plot (LTE Band 14 - 10MHz QPSK - RB Size 1, RB Offset 0 - Mid Channel)

Peak

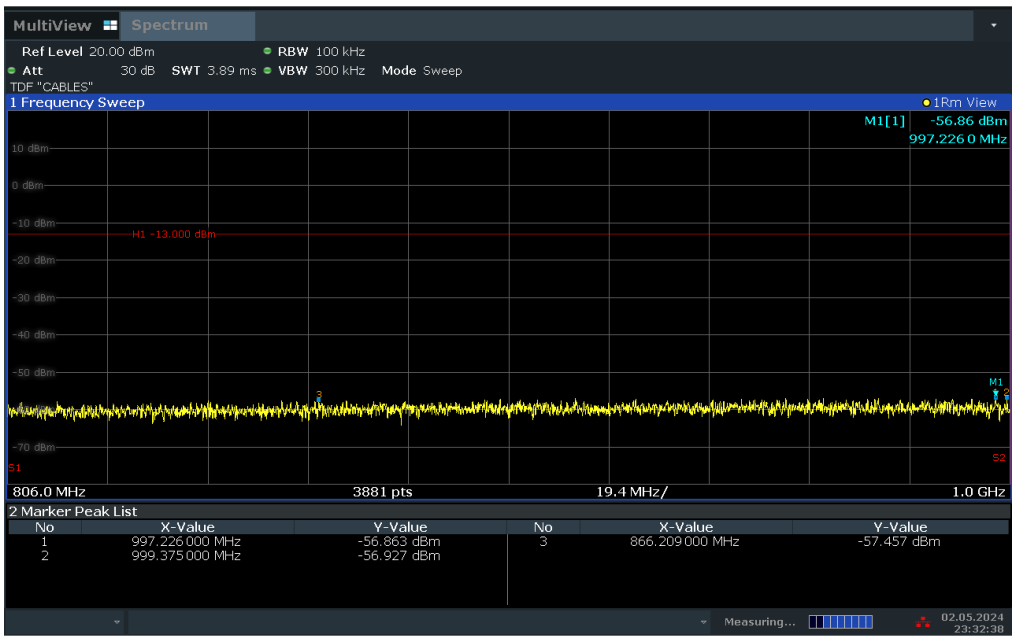


23:32:21 02.05.2024

Plot 7-63. Conducted Spurious Plot (LTE Band 14 - 10MHz QPSK - RB Size 1, RB Offset 0 - Mid Channel)

Unless otherwise specified, no part of this report may be reproduced or utilized in any part, form or by any means, electronic or mechanical, including photocopying and microfilm, without permission in writing from Element Materials Technology. If you have any questions about this or have an enquiry about obtaining additional rights to this report or assembly of contents thereof, please contact ct.info@element.com.

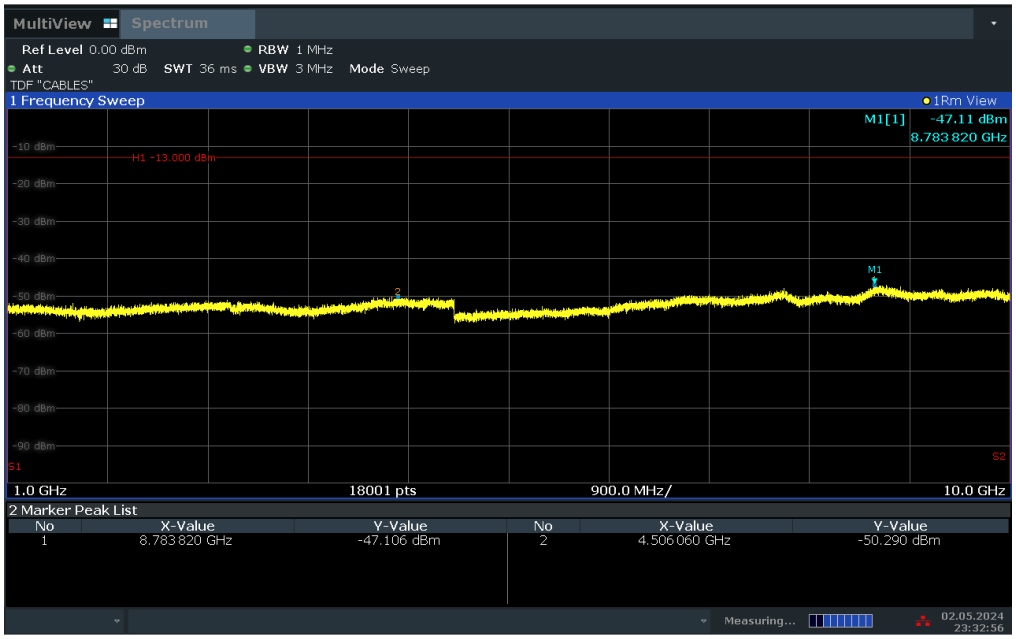
Peak



23:32:39 02.05.2024

Plot 7-64. Conducted Spurious Plot (LTE Band 14 - 10MHz QPSK - RB Size 1, RB Offset 0 - Mid Channel)

Peak

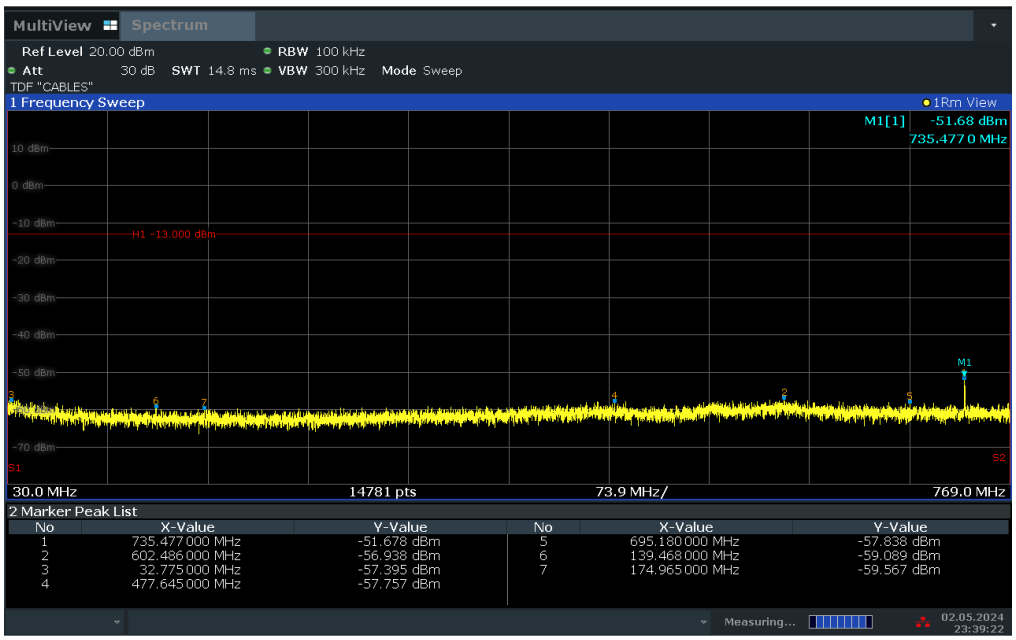


23:32:56 02.05.2024

Plot 7-65. Conducted Spurious Plot (LTE Band 14 - 10MHz QPSK - RB Size 1, RB Offset 0 - Mid Channel)

Unless otherwise specified, no part of this report may be reproduced or utilized in any part, form or by any means, electronic or mechanical, including photocopying and microfilm, without permission in writing from Element Materials Technology. If you have any questions about this or have an enquiry about obtaining additional rights to this report or assembly of contents thereof, please contact ct.info@element.com.

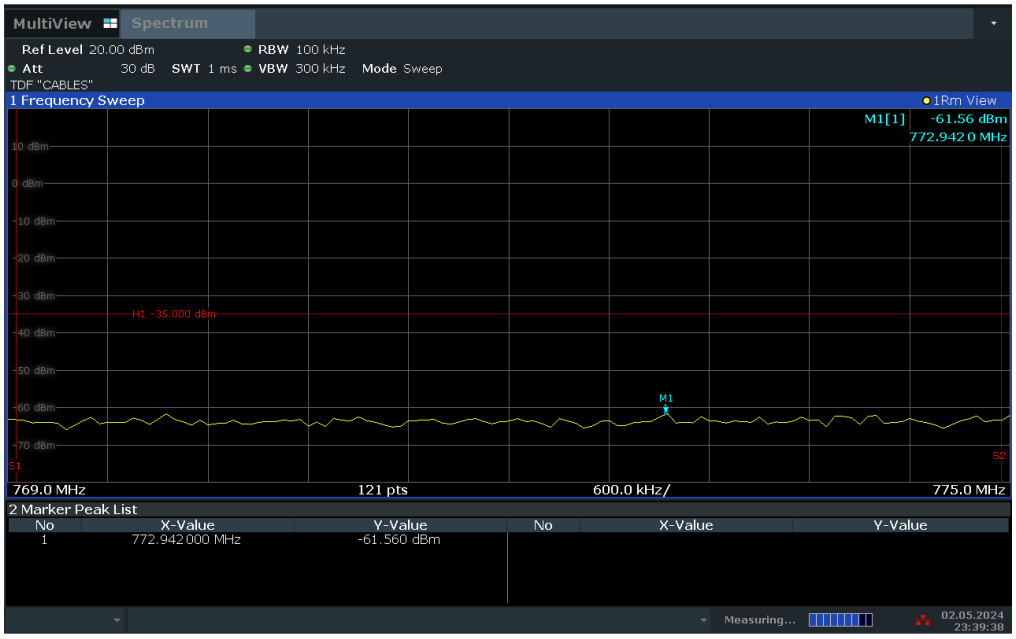
Peak



23:39:22 02.05.2024

Plot 7-66. Conducted Spurious Plot (LTE Band 14 - 5MHz QPSK - RB Size 1, RB Offset 0 - High Channel)

Peak

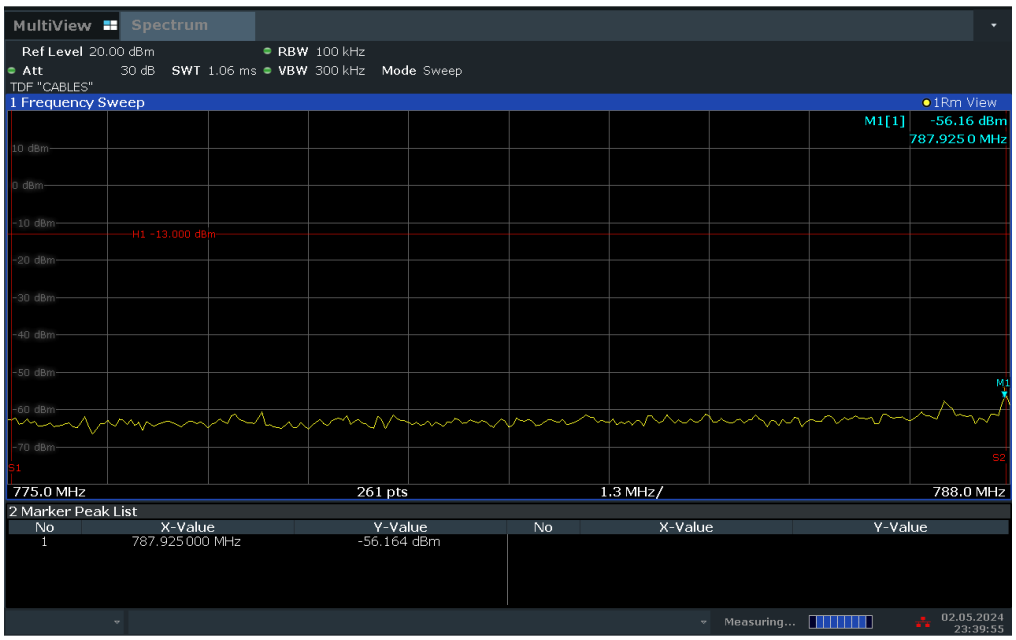


23:39:39 02.05.2024

Plot 7-67. Conducted Spurious Plot (LTE Band 14 - 5MHz QPSK - RB Size 1, RB Offset 0 - High Channel)

Unless otherwise specified, no part of this report may be reproduced or utilized in any part, form or by any means, electronic or mechanical, including photocopying and microfilm, without permission in writing from Element Materials Technology. If you have any questions about this or have an enquiry about obtaining additional rights to this report or assembly of contents thereof, please contact ct.info@element.com.

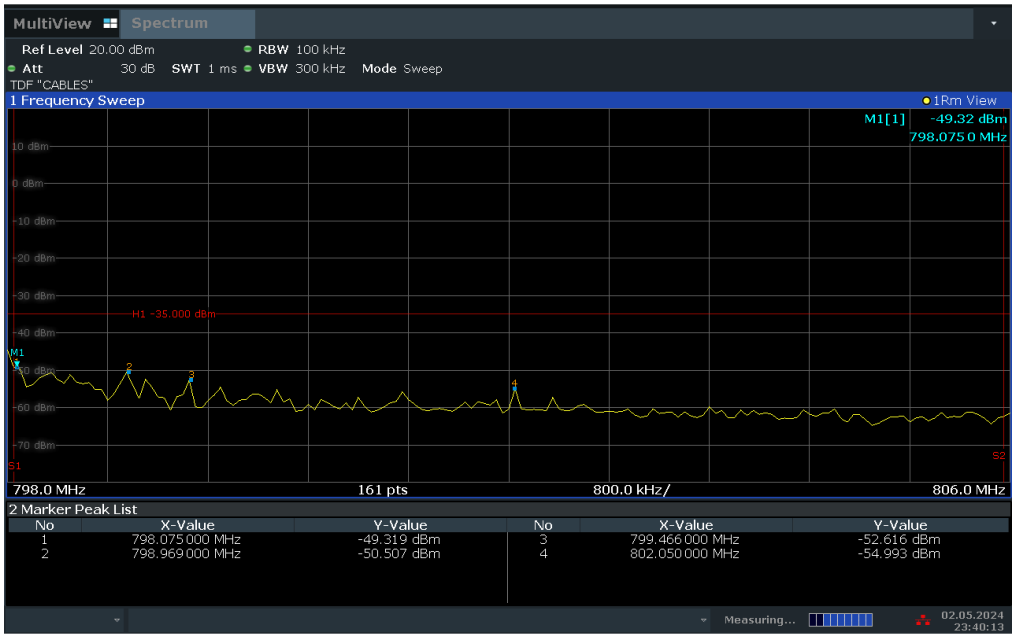
Peak



23:39:56 02.05.2024

Plot 7-68. Conducted Spurious Plot (LTE Band 14 - 5MHz QPSK - RB Size 1, RB Offset 0 - High Channel)

Peak

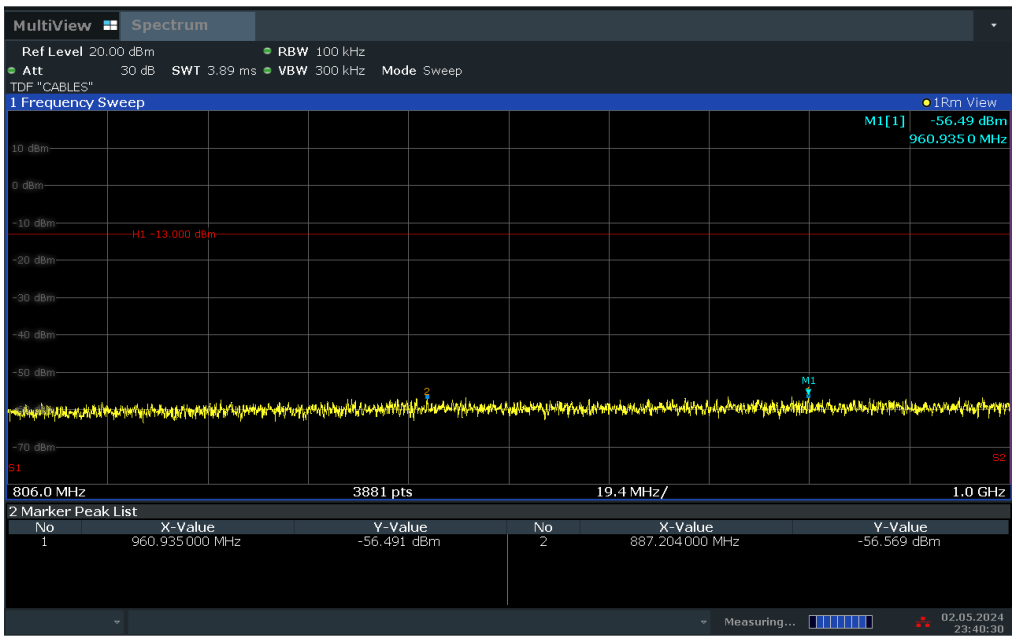


23:40:13 02.05.2024

Plot 7-69. Conducted Spurious Plot (LTE Band 14 - 5MHz QPSK - RB Size 1, RB Offset 0 - High Channel)

Unless otherwise specified, no part of this report may be reproduced or utilized in any part, form or by any means, electronic or mechanical, including photocopying and microfilm, without permission in writing from Element Materials Technology. If you have any questions about this or have an enquiry about obtaining additional rights to this report or assembly of contents thereof, please contact ct.info@element.com.

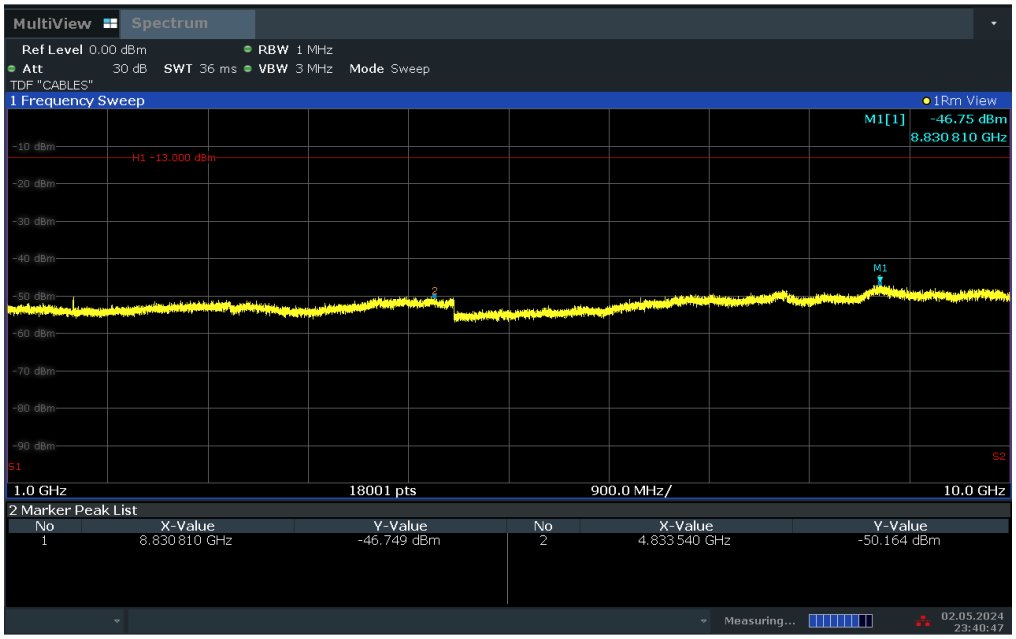
Peak



23:40:30 02.05.2024

Plot 7-70. Conducted Spurious Plot (LTE Band 14 - 5MHz QPSK - RB Size 1, RB Offset 0 - High Channel)

Peak

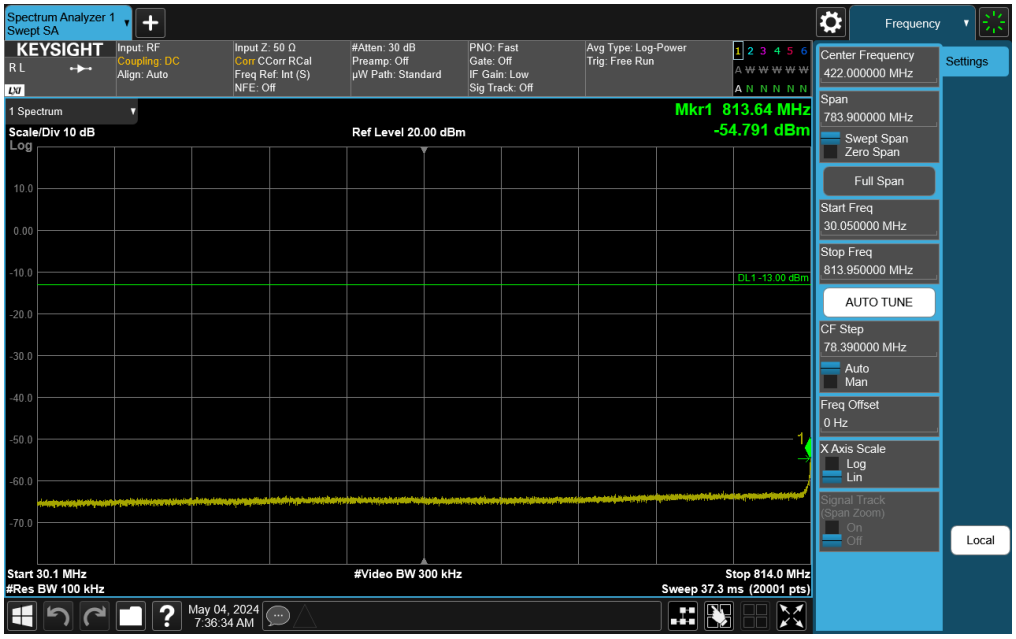


23:40:47 02.05.2024

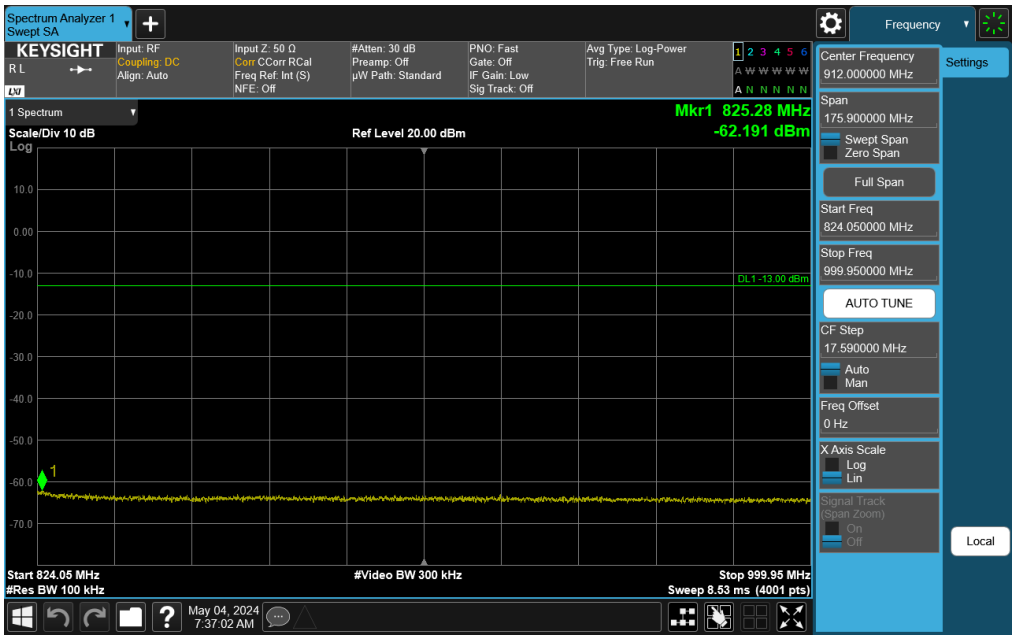
Plot 7-71. Conducted Spurious Plot (LTE Band 14 - 5MHz QPSK - RB Size 1, RB Offset 0 - High Channel)

Unless otherwise specified, no part of this report may be reproduced or utilized in any part, form or by any means, electronic or mechanical, including photocopying and microfilm, without permission in writing from Element Materials Technology. If you have any questions about this or have an enquiry about obtaining additional rights to this report or assembly of contents thereof, please contact ct.info@element.com.

NR Band 26



Plot 7-72. Conducted Spurious Plot (NR Band 26 - 5MHz DFT-s-OFDM QPSK - RB Size 1, RB Offset 0 - Low Channel)



Plot 7-73. Conducted Spurious Plot (NR Band 26 - 5MHz DFT-s-OFDM QPSK - RB Size 1, RB Offset 0 - Low Channel)

Unless otherwise specified, no part of this report may be reproduced or utilized in any part, form or by any means, electronic or mechanical, including photocopying and microfilm, without permission in writing from Element Materials Technology. If you have any questions about this or have an enquiry about obtaining additional rights to this report or assembly of contents thereof, please contact ct.info@element.com.